

Electrical Breakdown Involving a Gas-Solid Interface

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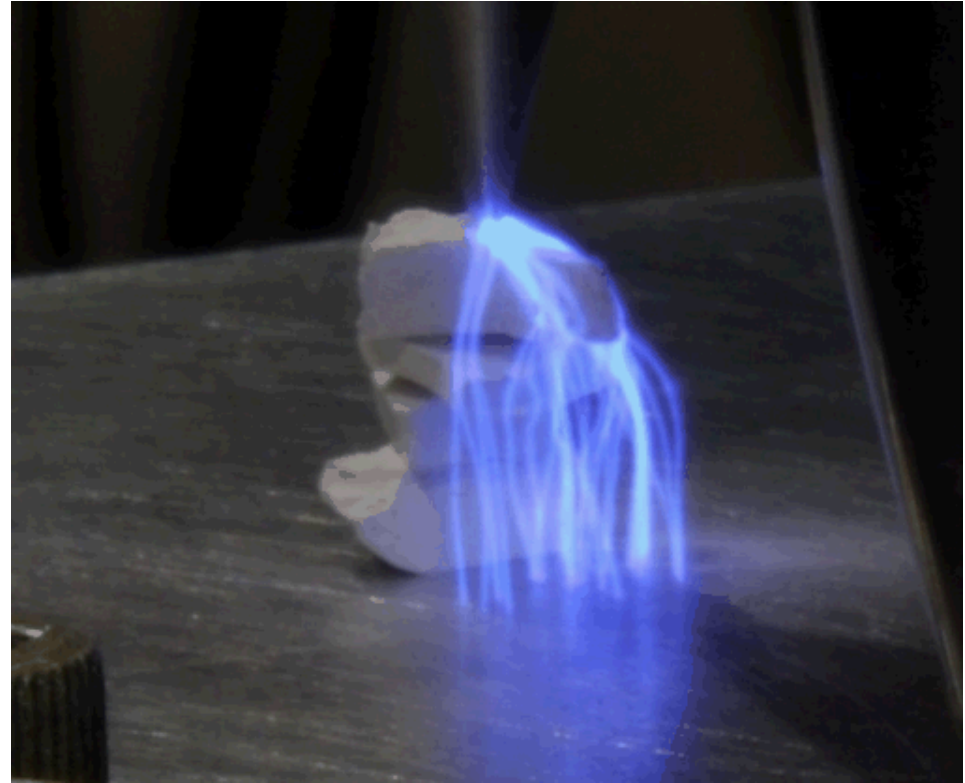
Electrical Breakdown of TiO₂ Particles

Experiments image the breakdown path across TiO₂ particles

The images reveal that breakdown occurs either across a particle surface or through pores in a particle

These experiments led to my hypothesis that thermal breakdown explains this and other data

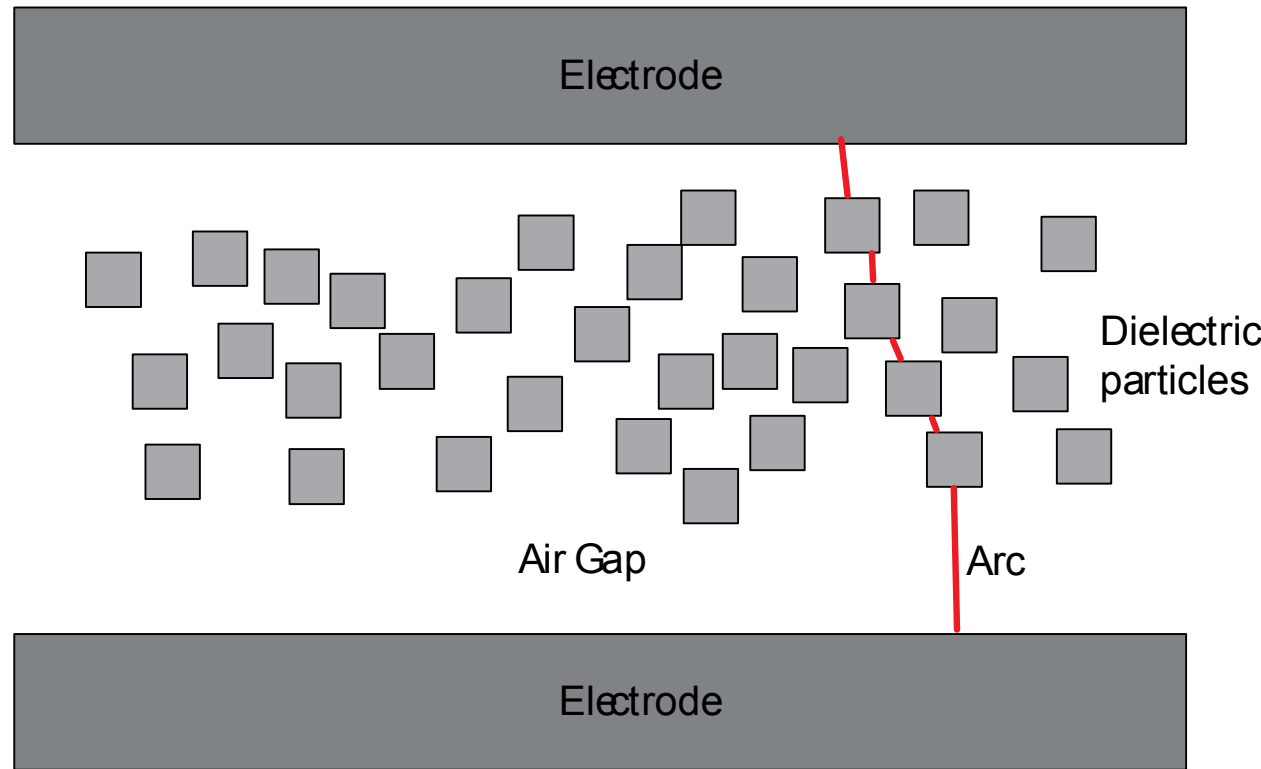
Initial experiments by Jane Lehr;
more recent experiments by Ken
Williamson



Electrical breakdown “hugging” the rutile surface

Lightning Arrester: Idealized Structure

Purpose: Closing switch that diverts lightning transient current to an electrical ground



Project goal: Develop a physics-based model to improve understanding and performance

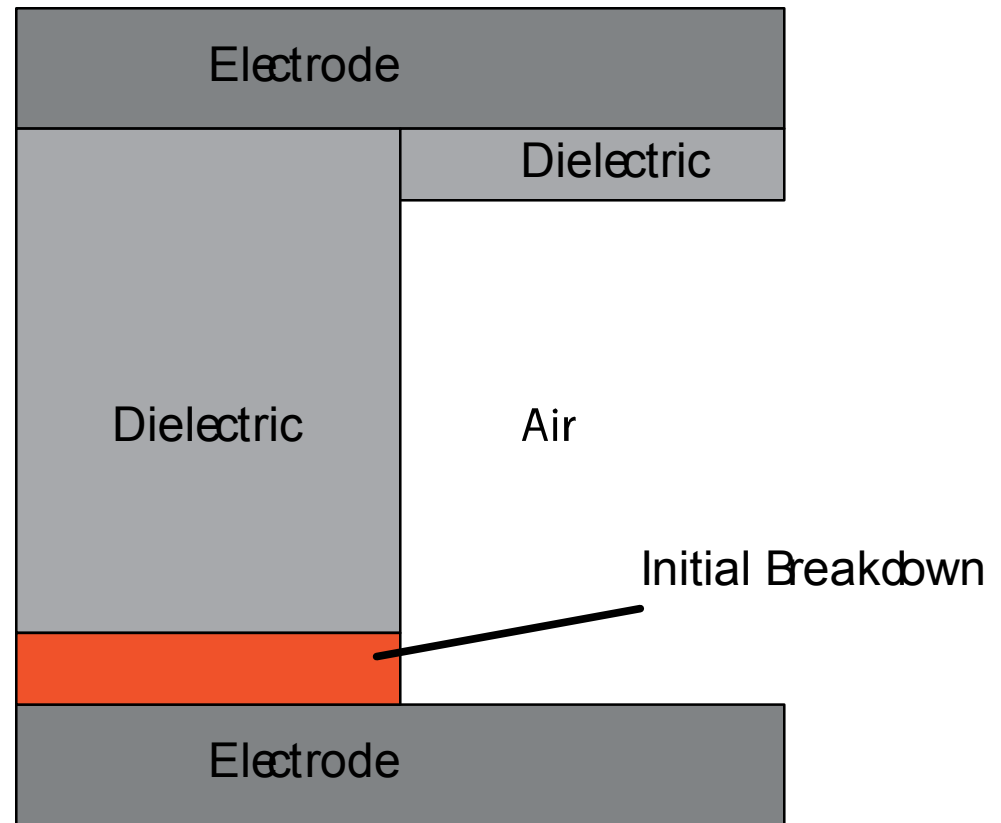
Outline

- **Motivation**
 - High permittivity dielectrics used since earliest lightning arresters in 1920's
 - Understand the physics effects of a high permittivity dielectric
- **Simple Structures and Calculations**
 - 1D calculations focused on early time breakdown
 - Tunneling
 - 2D calculations focused on late time effects
 - Electrothermal breakdown
- **Physics**
 - Early time: Townsend mechanism
 - Intermediate time: Cathode tunneling
 - Late time: Triggered breakdown of the entire structure

Breakdown in Small Air Gaps

High permittivity dielectric
acts like a metal at short times

The fast breakdown in the small
gap triggers breakdown in the
large gap



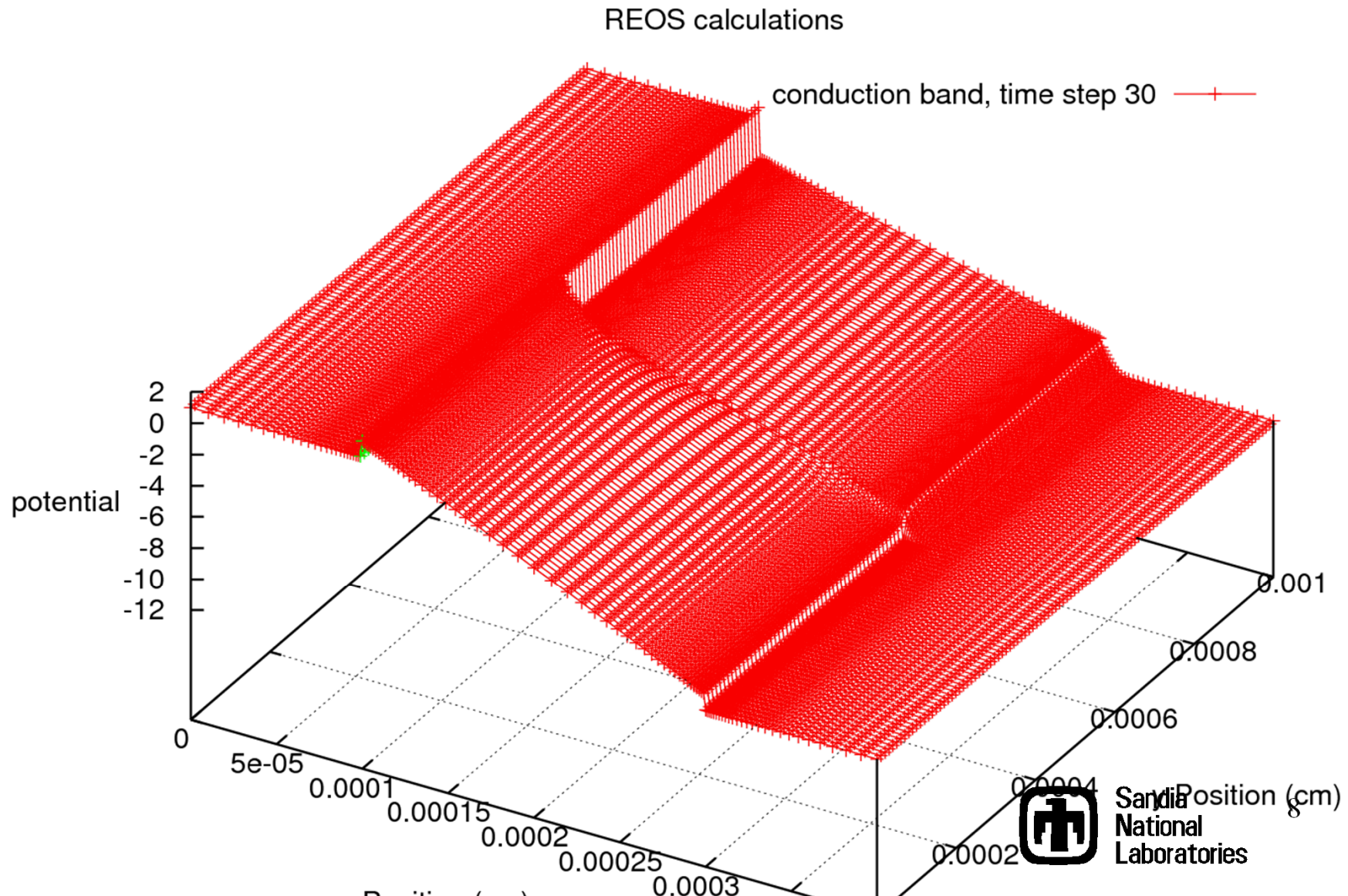
Two Types of Initial Events

- **Small gap**
 - Tunneling produces an initial density
 - Avalanche growth
- **Large gap**
 - Background radiation produces an initial density
 - Avalanche growth

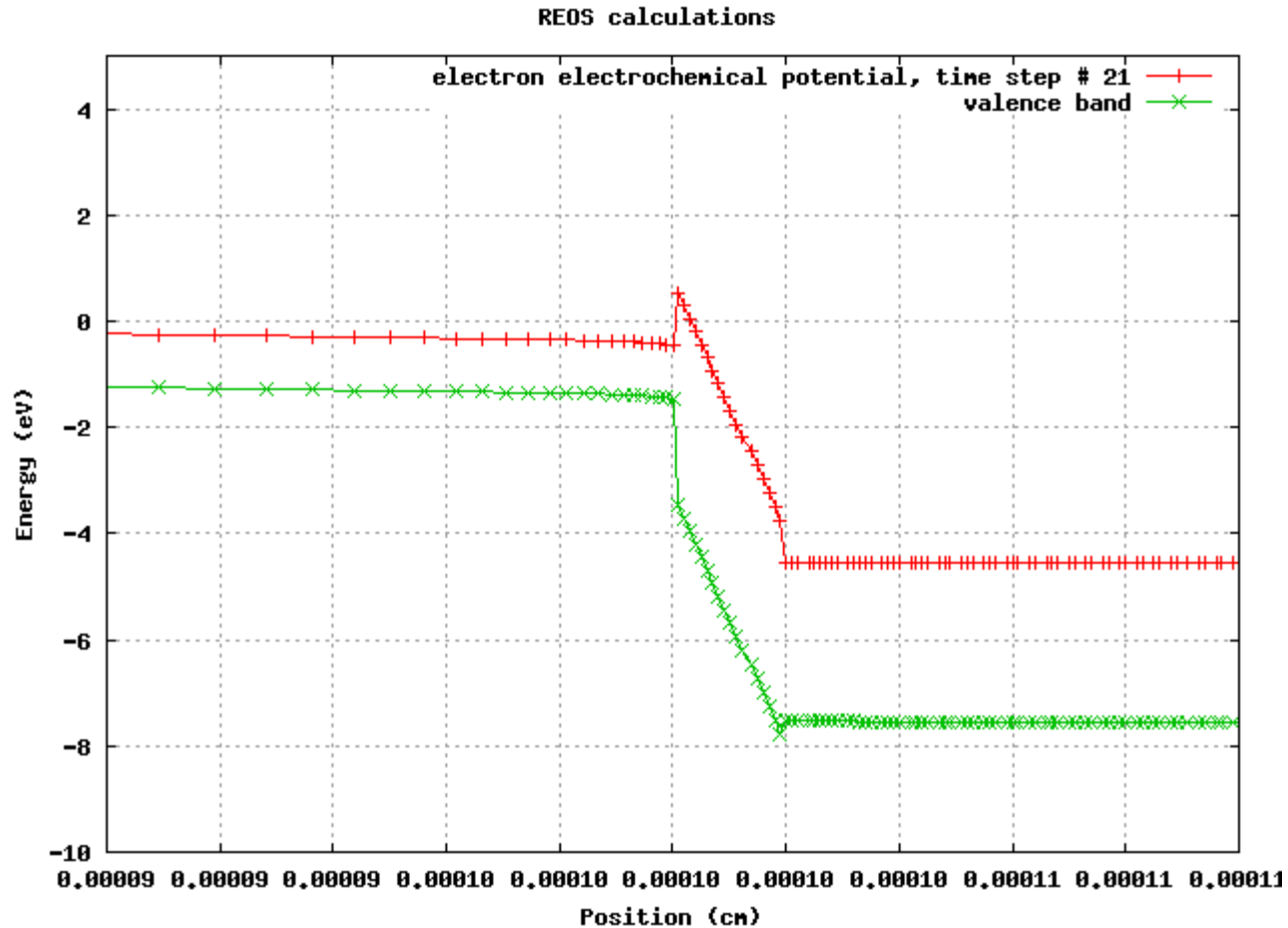
Small Gaps

- **Very small: $L = 10^{-4}$ cm**
- **The large electric field causes tunneling**

Large Electric Field in the Air Gap



Tunneling in the High Field Region



Large Gaps

A crude rate equation

$$\frac{\partial n}{\partial t} = R - Tn + Sn + An$$

R = Ionizing radiation rate

T = Transport removal of electrons

S = Secondary injection of electrons: photoemission (PE)
and secondary electron emission (SEE)

A = Avalanche creation of electron-ion pairs

Time Evolution: Initial Density

An initial density is set by the applied field

$$\frac{\partial n}{\partial t} = R - Tn$$

Steady state: $\frac{\partial n}{\partial t} = 0$

$$n_0 = R / T$$

$$R = 0.01 \text{ Rad/s, assume Rad} = 10^{13} \text{ e-ion cm}^{-3} \text{ sec}^{-1}$$

$$T = V / L = 10^7 \text{ sec}^{-1}$$

$$\text{Using } V = 10^6 \text{ cm/sec and } L = 10^{-1} \text{ cm}$$

$$T = V / L = 10^7 \text{ sec}^{-1}$$

Assembling

$$n_0 = R / T = 10^4 \text{ cm}^{-3}$$

Time Evolution: Growth

Now focus on the avalanche term

$$\frac{\partial n}{\partial t} = R - Tn + Sn + An$$

Assume large voltage; then the avalanche term dominates

$$\frac{\partial n}{\partial t} = An$$

$$n(t) = n_0 e^{At} \text{ with}$$

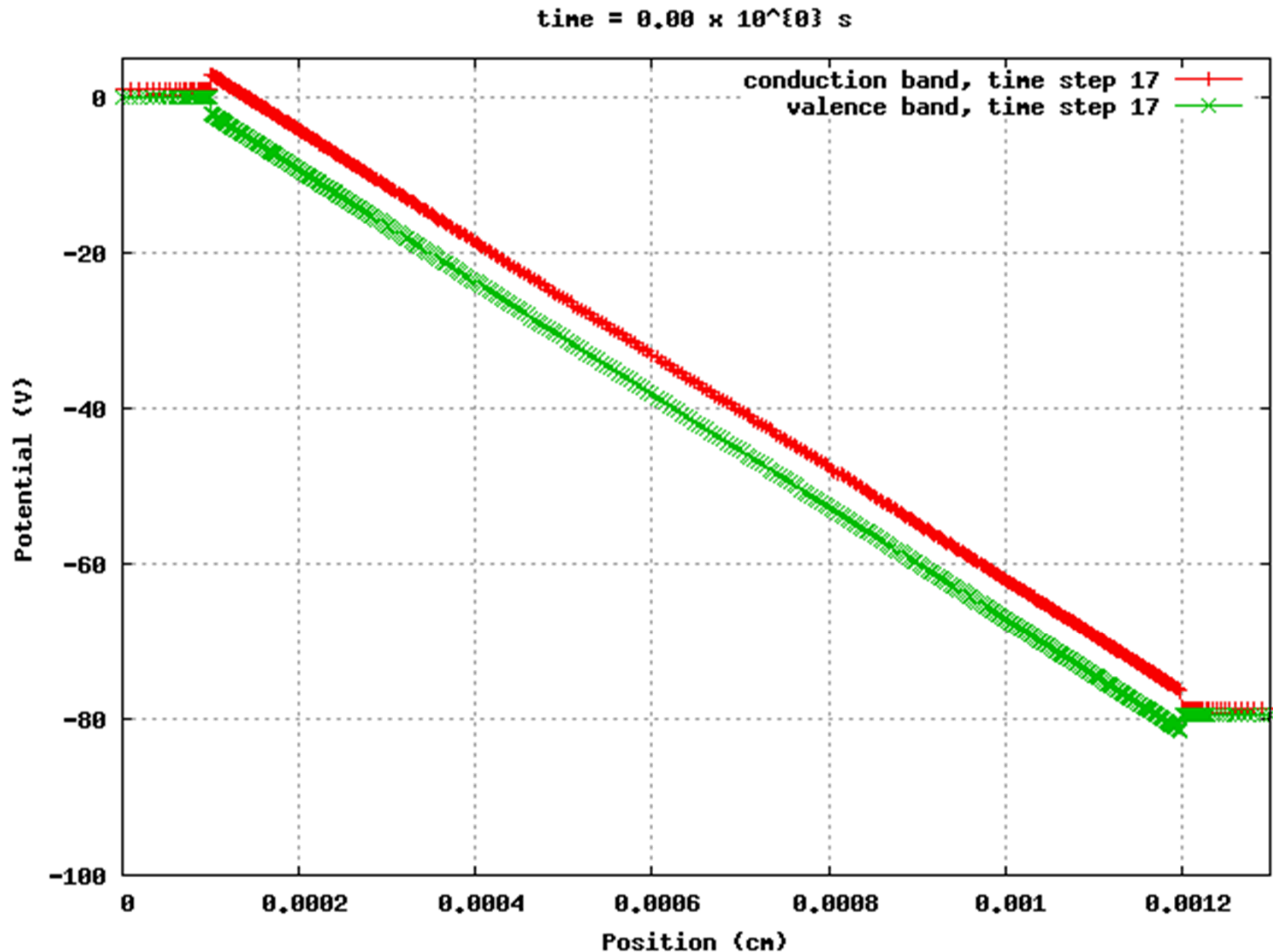
$$n_0 = 10^4 \text{ cm}^{-3}$$

Very rapid growth if the field is very large

Calculations

- **Composite dielectric**
 - Air
 - Rutile
- **Townsend mechanism**
- **Results**
 - Breakdown occurs from numerical noise
 - Current flows through the electron-blocking contact

Air Gap Breakdown: Townsend Mechanism



Breakdown: Temporal Sequence



Physics

- **Initial breakdown**
 - Tunneling if the air gap is very small
 - Townsend mechanism in the air gap
 - Rapid growth of electrons and ions
- **Intermediate breakdown**
 - Electron flow increases the electric field (spatial separation of electrons and ions)
 - Tunneling injection of electrons from the cathode
- **Final breakdown**
 - Electrons and photons from the small gap initiate breakdown in the large gap

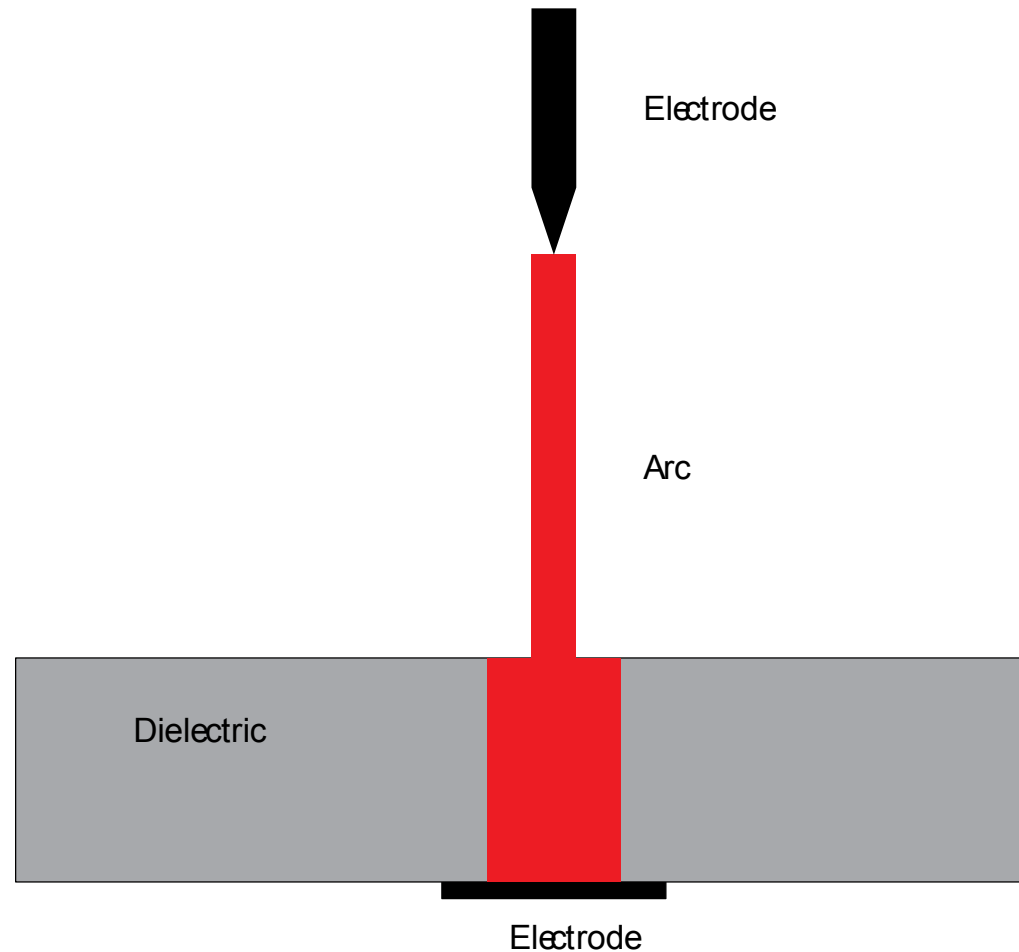


Idealized Structure and Experiment: Vertical

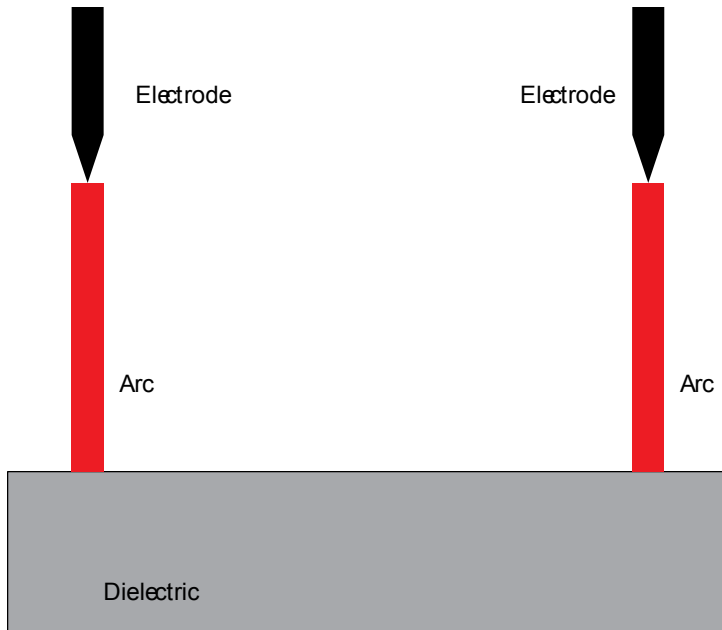
Short times: The insulating dielectric acts like an electrode to cause air breakdown

Intermediate times: Space charge limited current flows in the solid dielectric

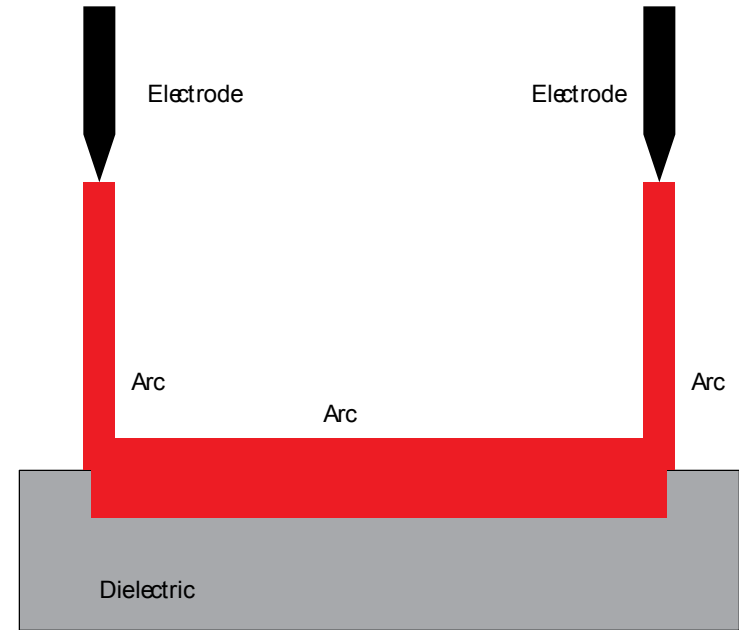
Long times: Either electrothermal breakdown from Joule heating or quenching of the air arc by deposited charge



Idealized Structure and Experiment



Early times: Air breakdown with the dielectric acting like a metal



Late times: Very conductive air breakdown causes breakdown of the solid dielectric

TiO_2 (rutile) has a large dielectric constant, approximately 86

Summary

- **Small air gap**
 - Tunneling causes breakdown
- **Large air gap**
 - Air breakdown at short times
 - Tunneling



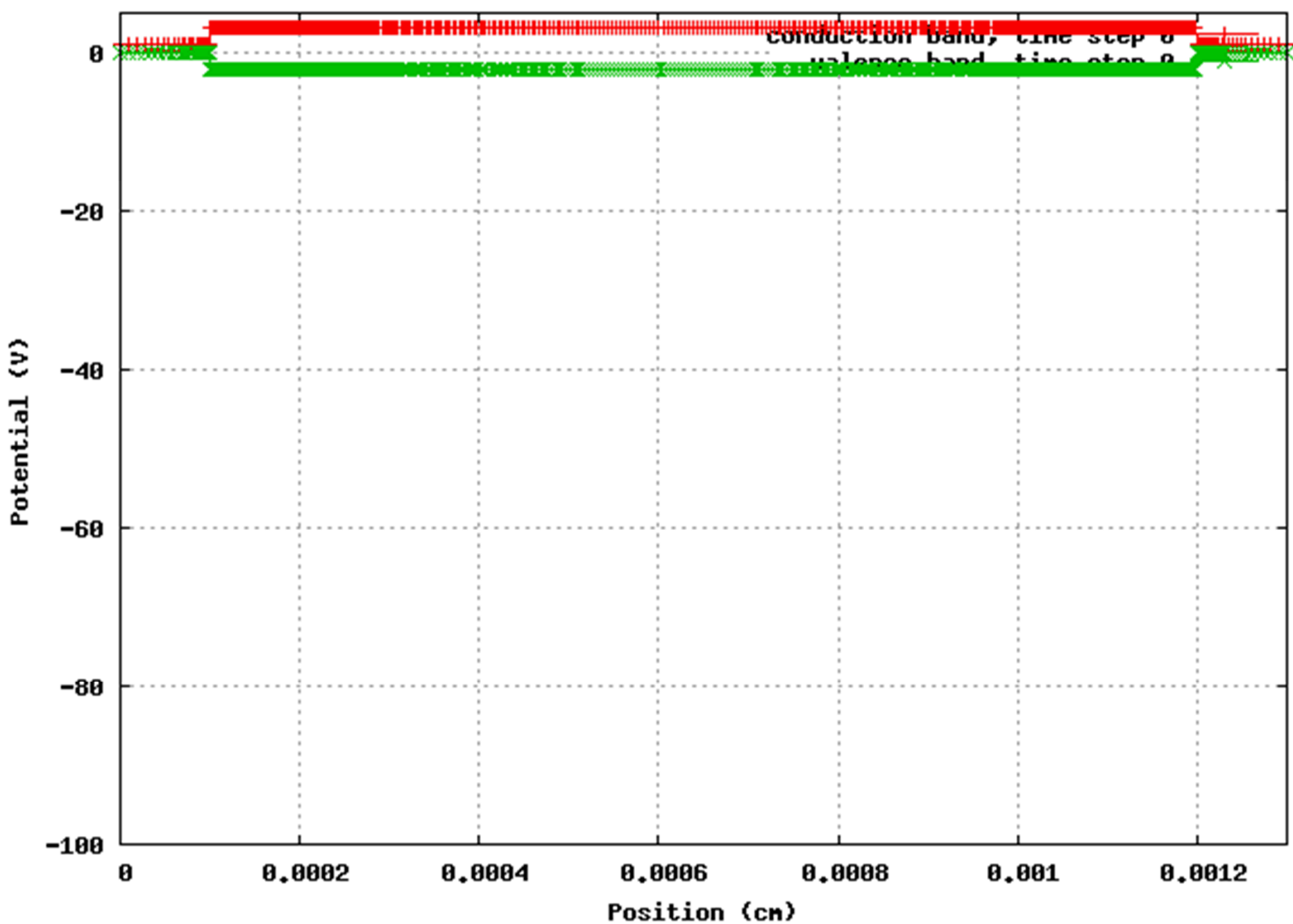
Breakdown: Temporal Sequence



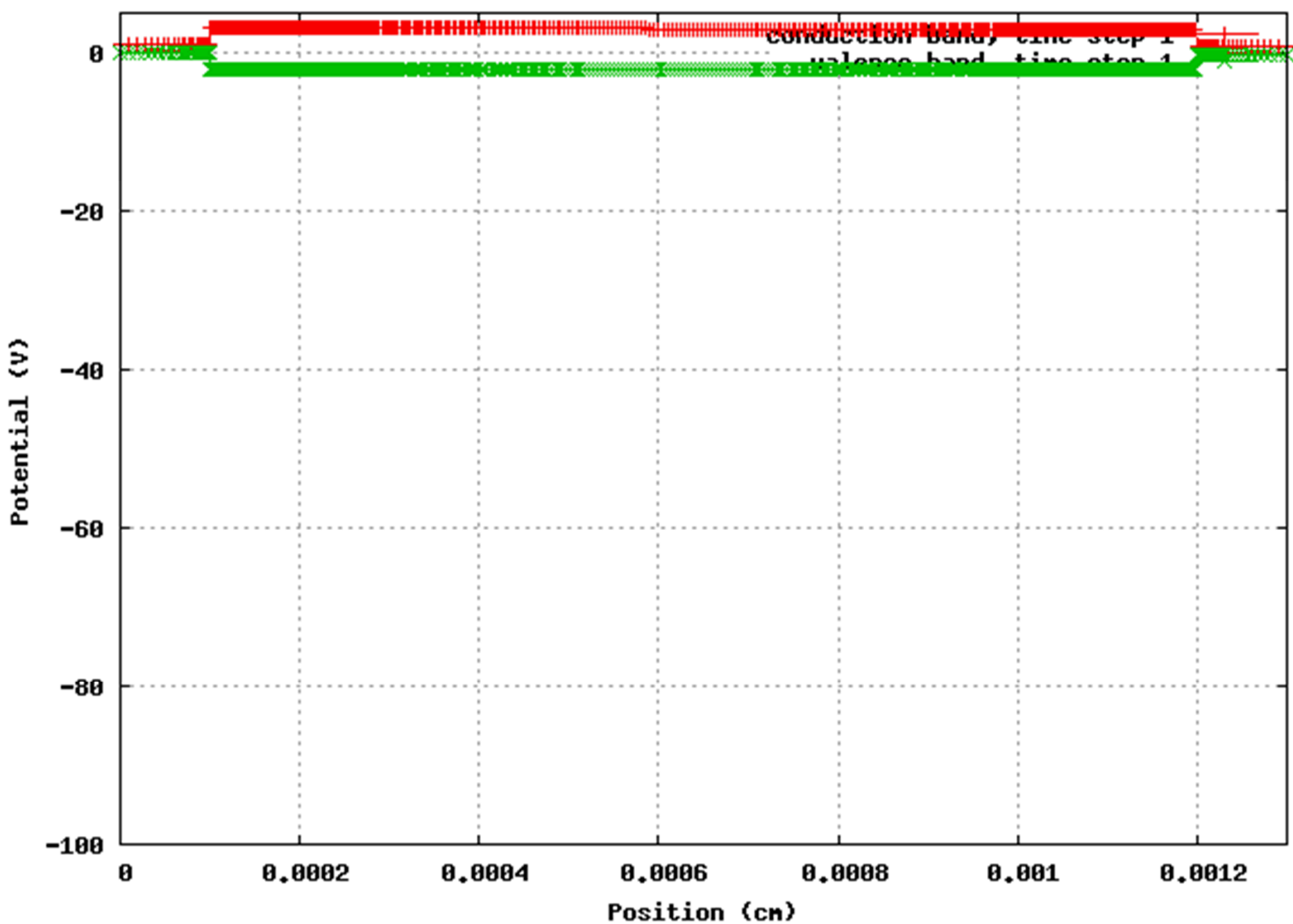
Photo Album

by Hjalmarson, Harold P

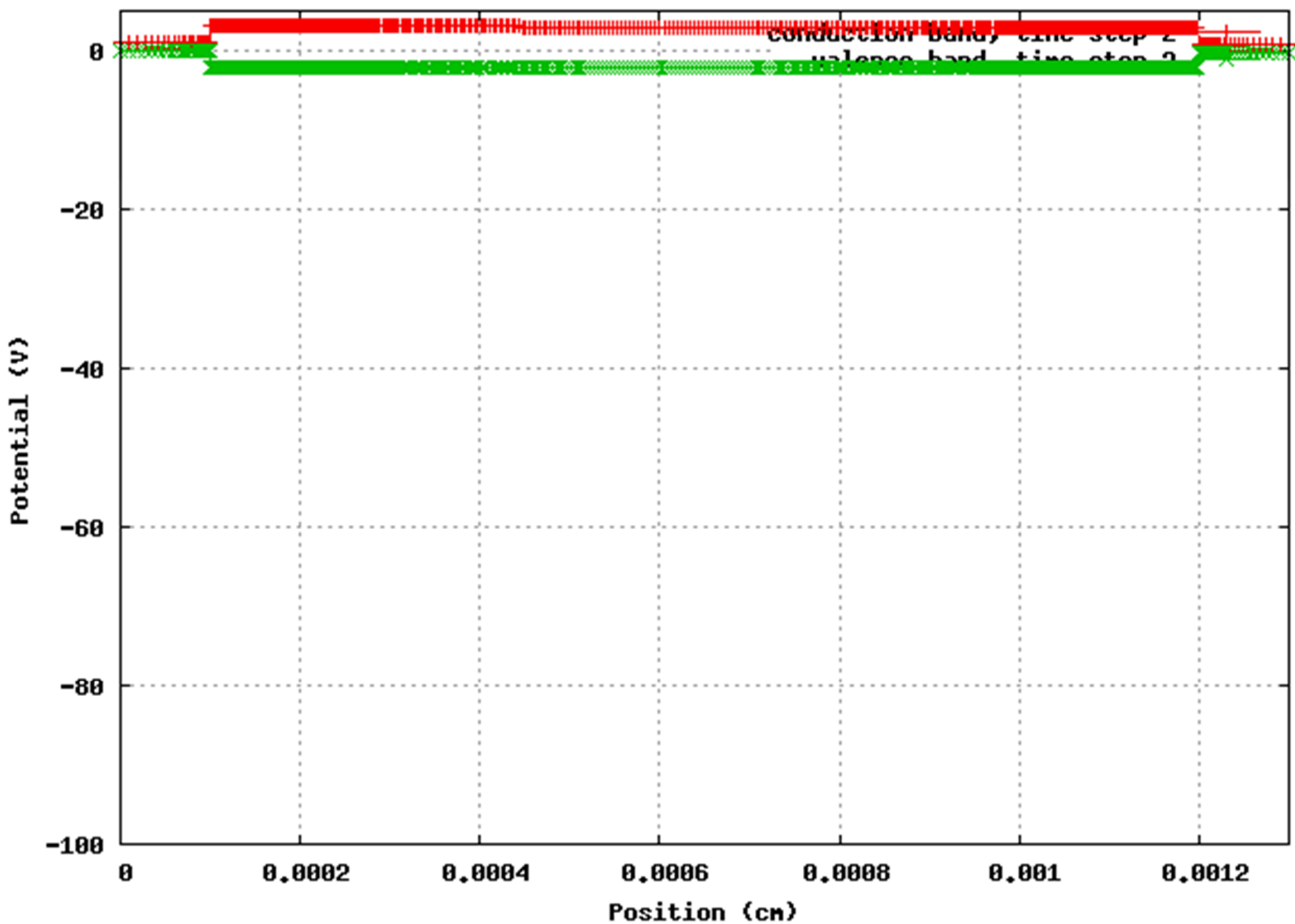
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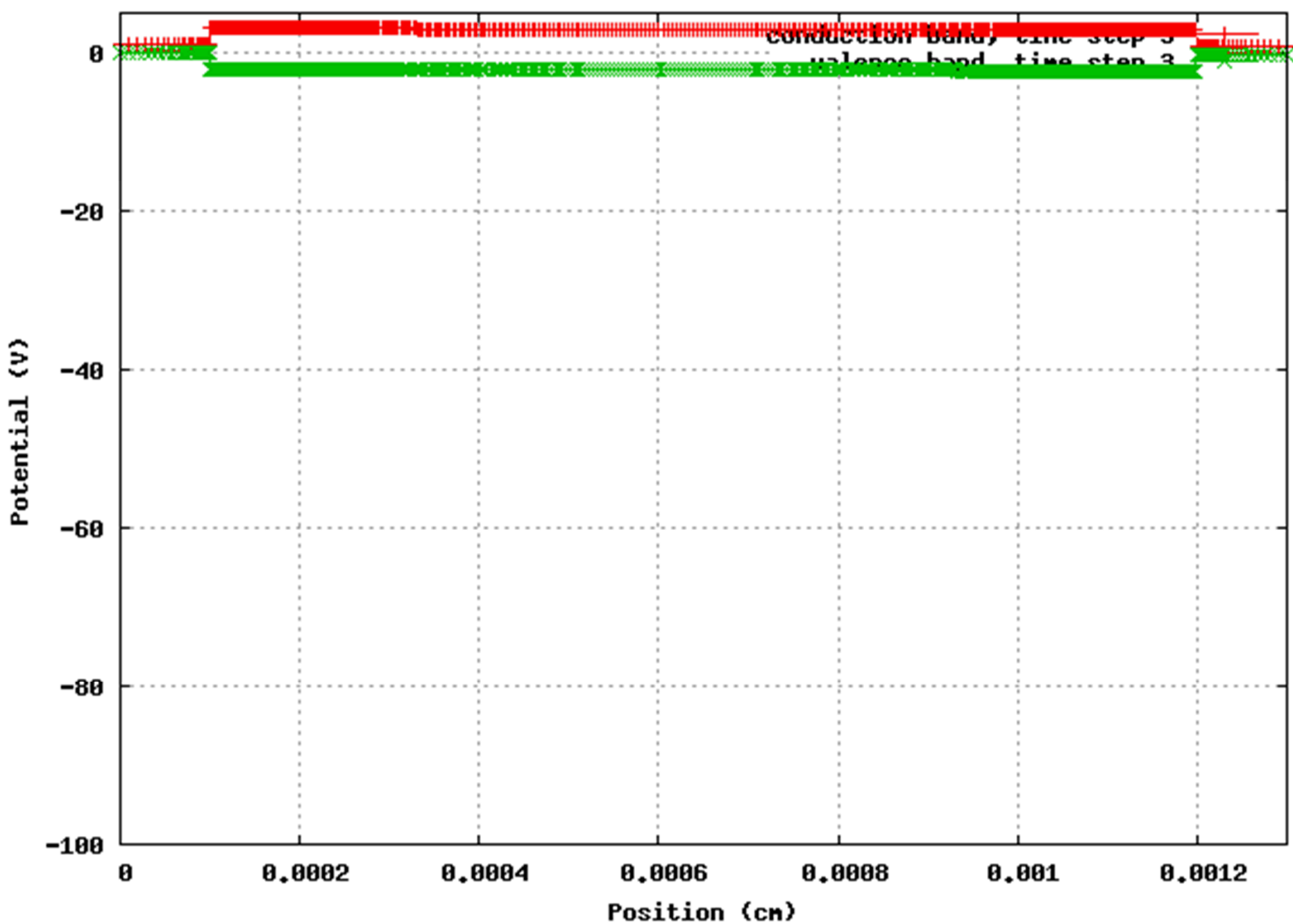
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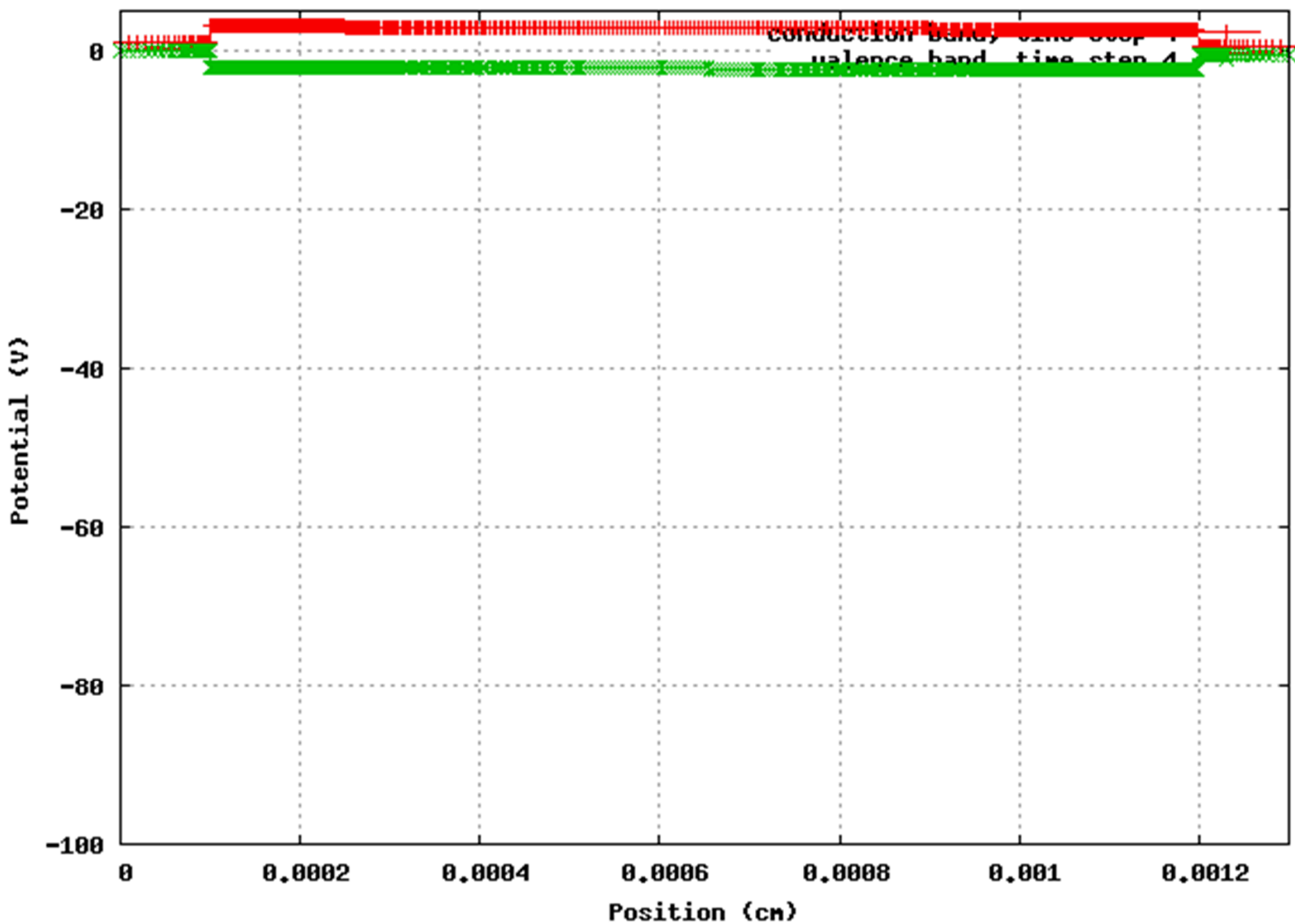
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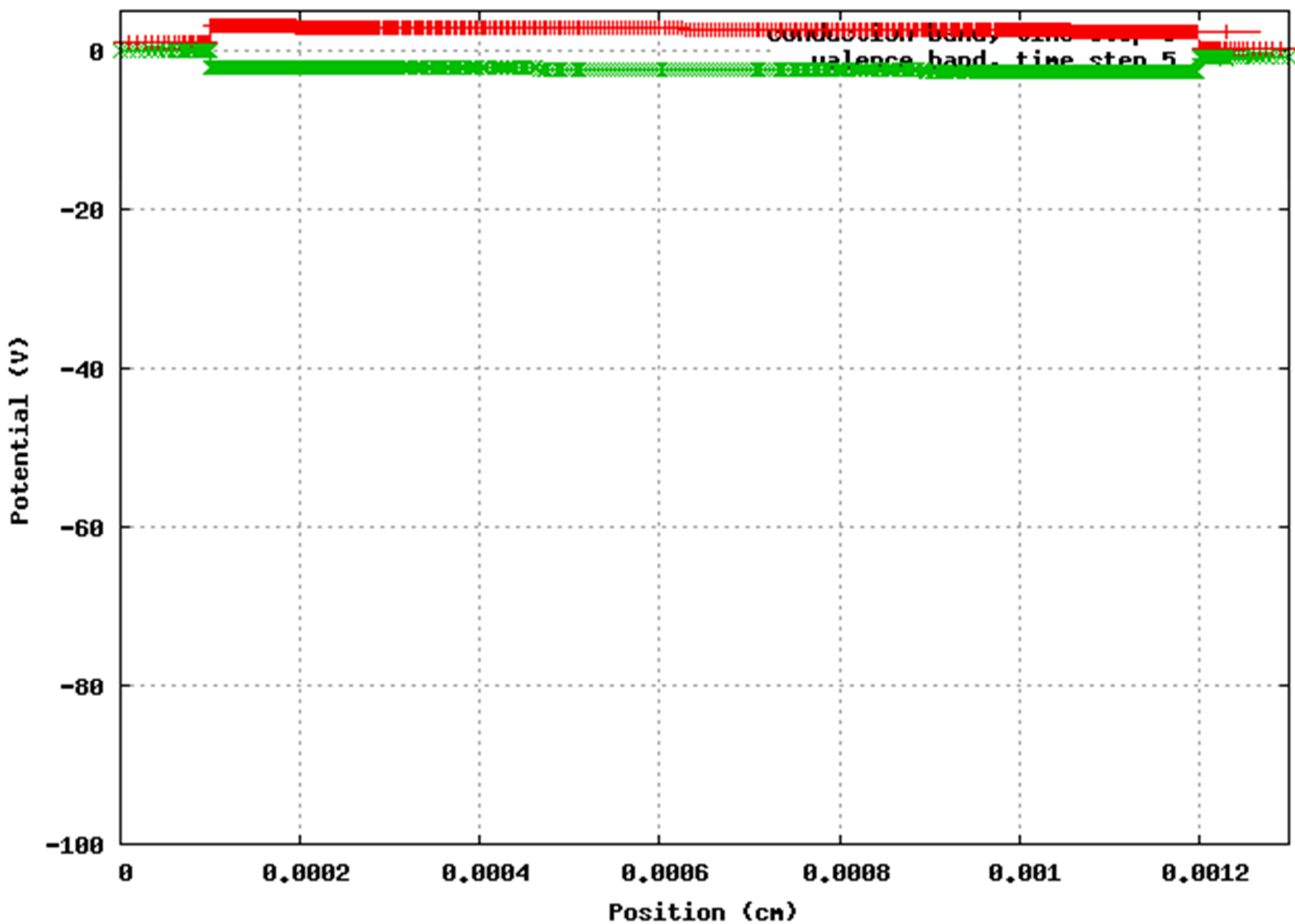
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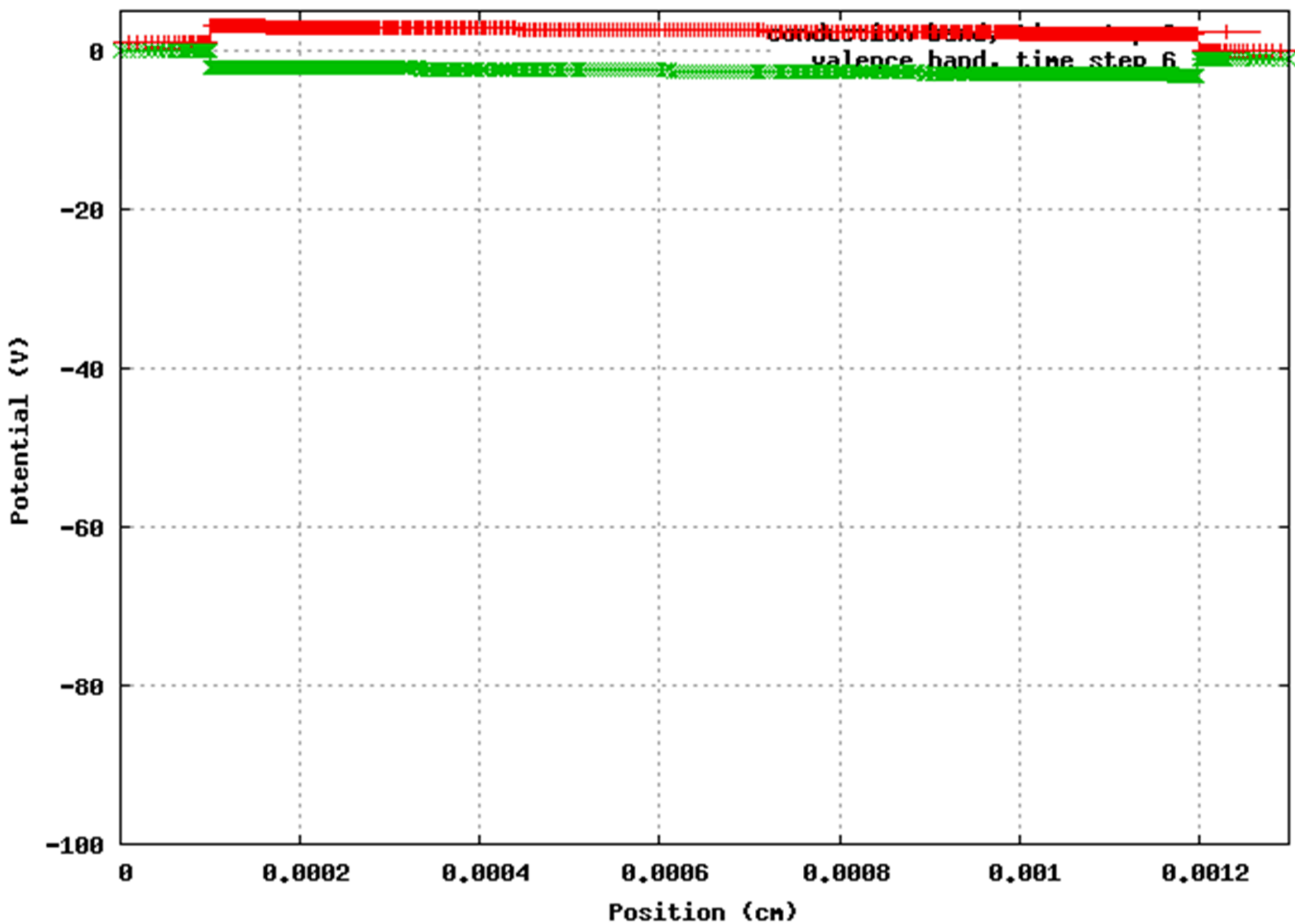
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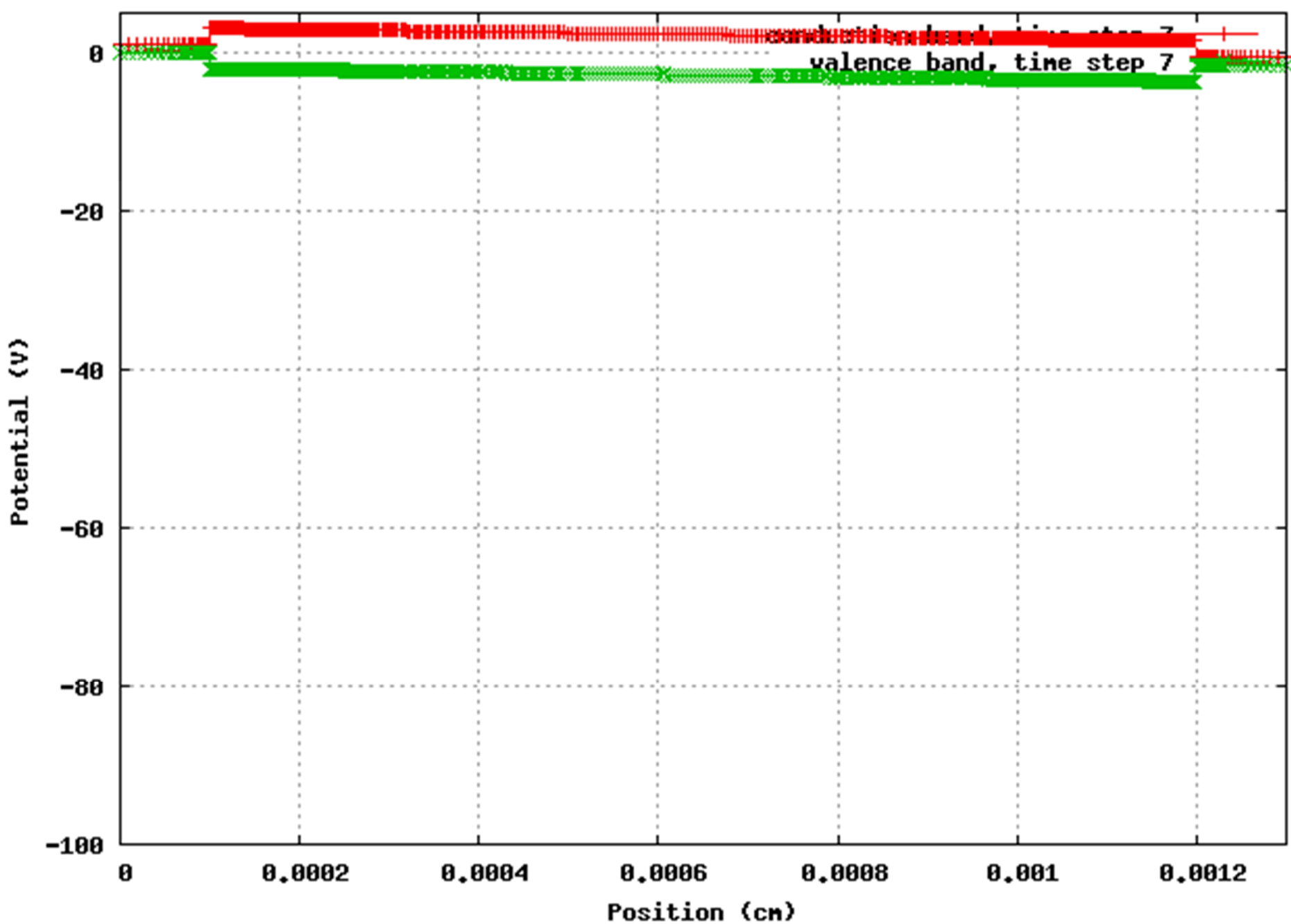
time = 0.00 x 10^{0} s



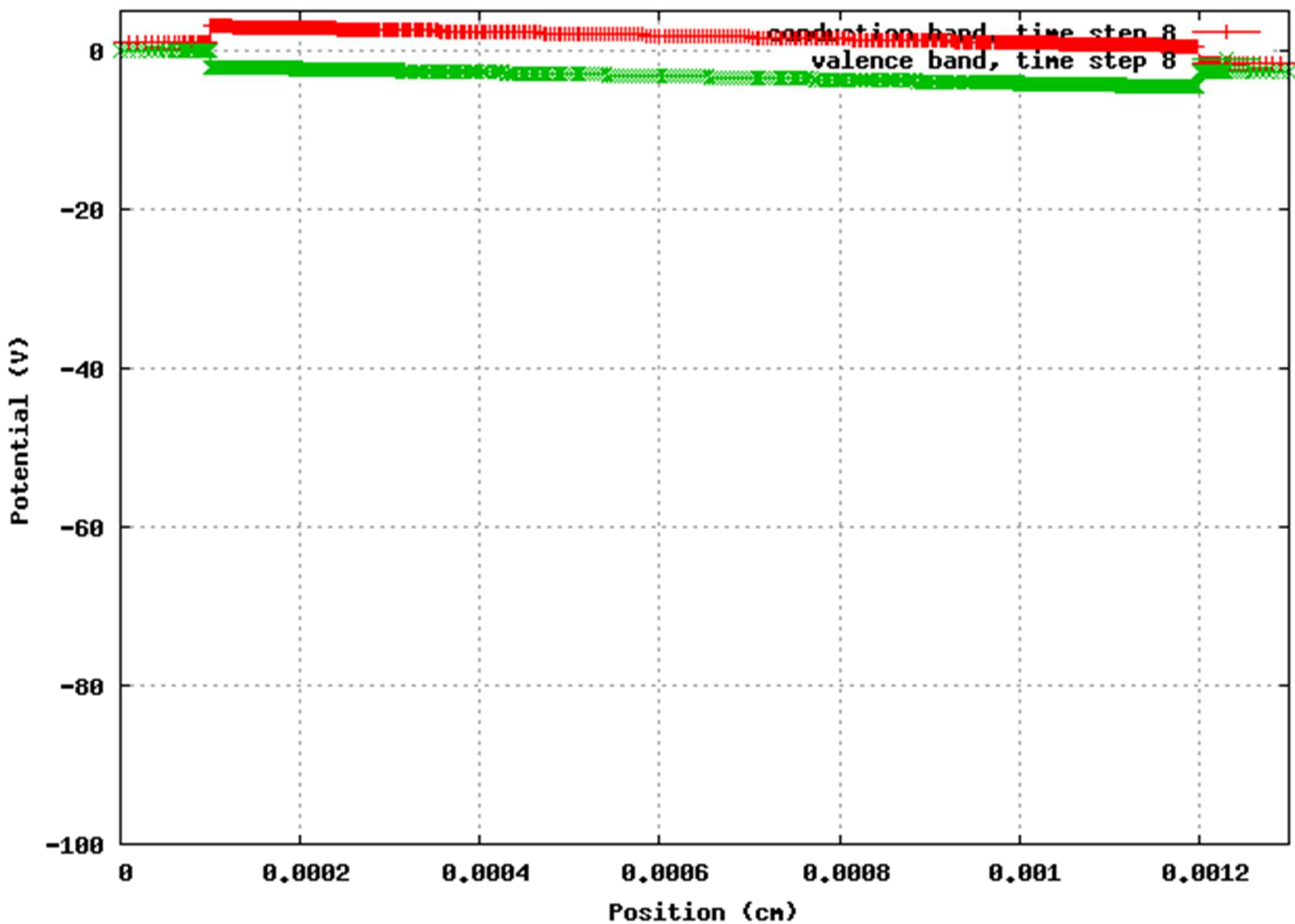
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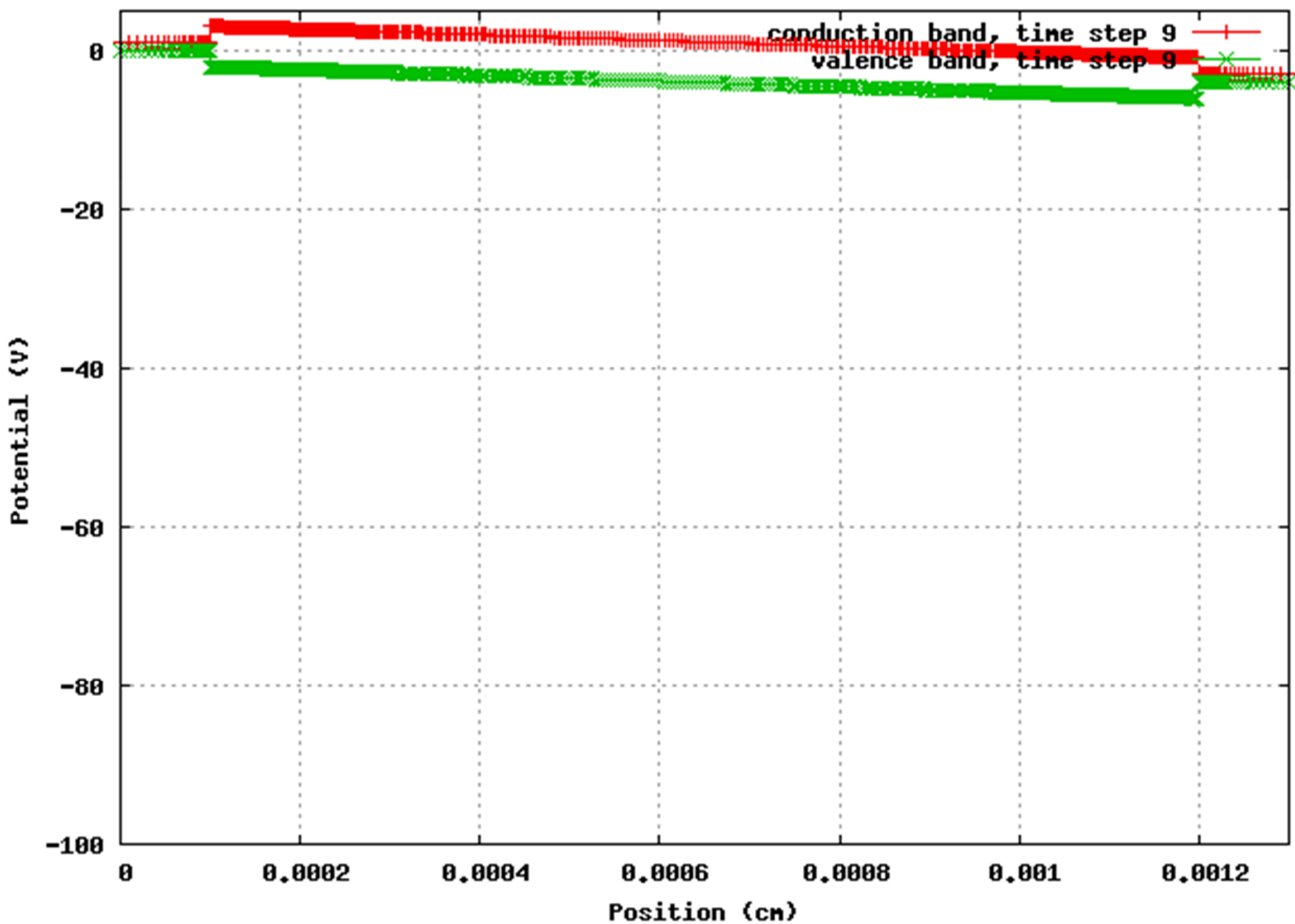
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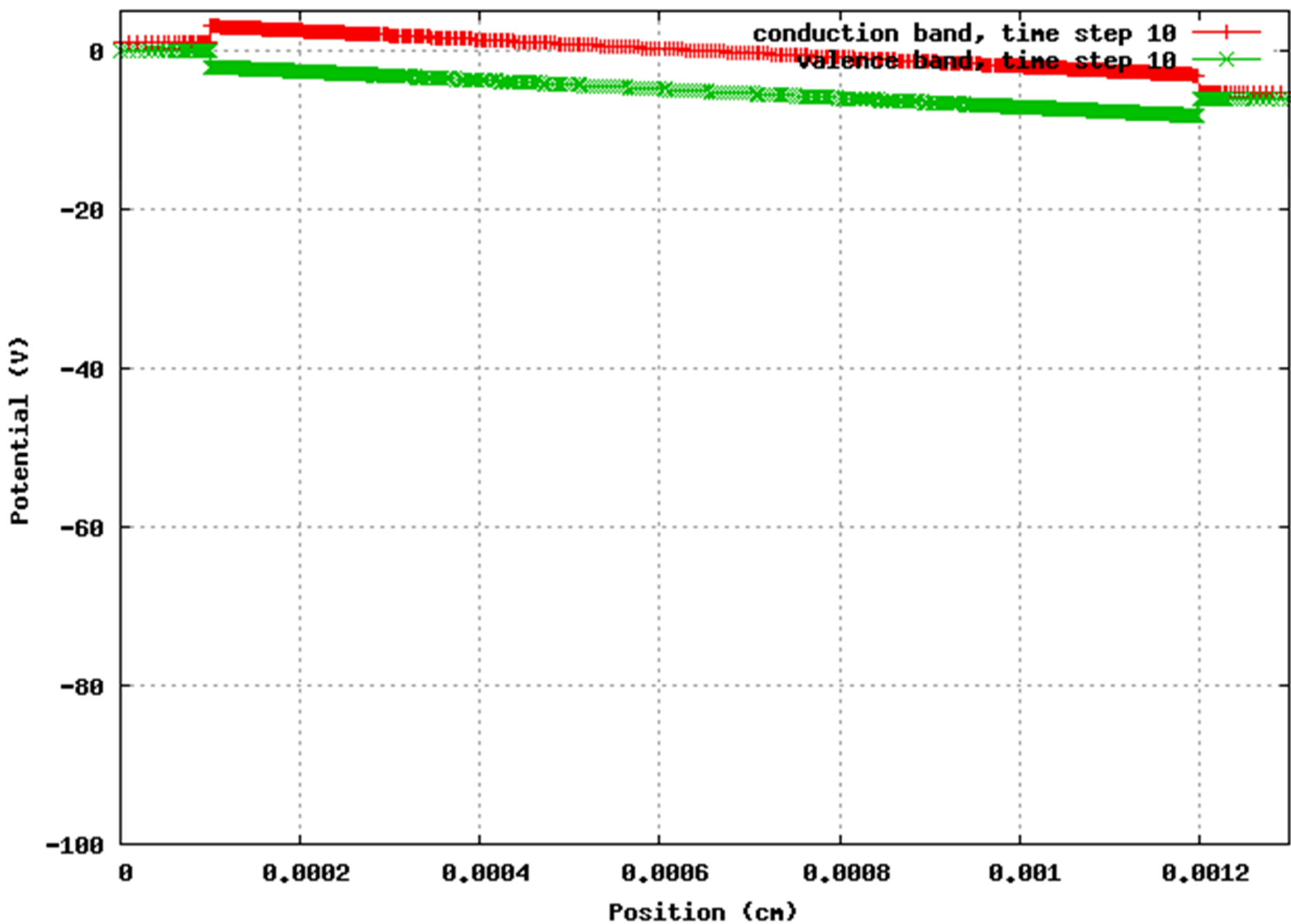
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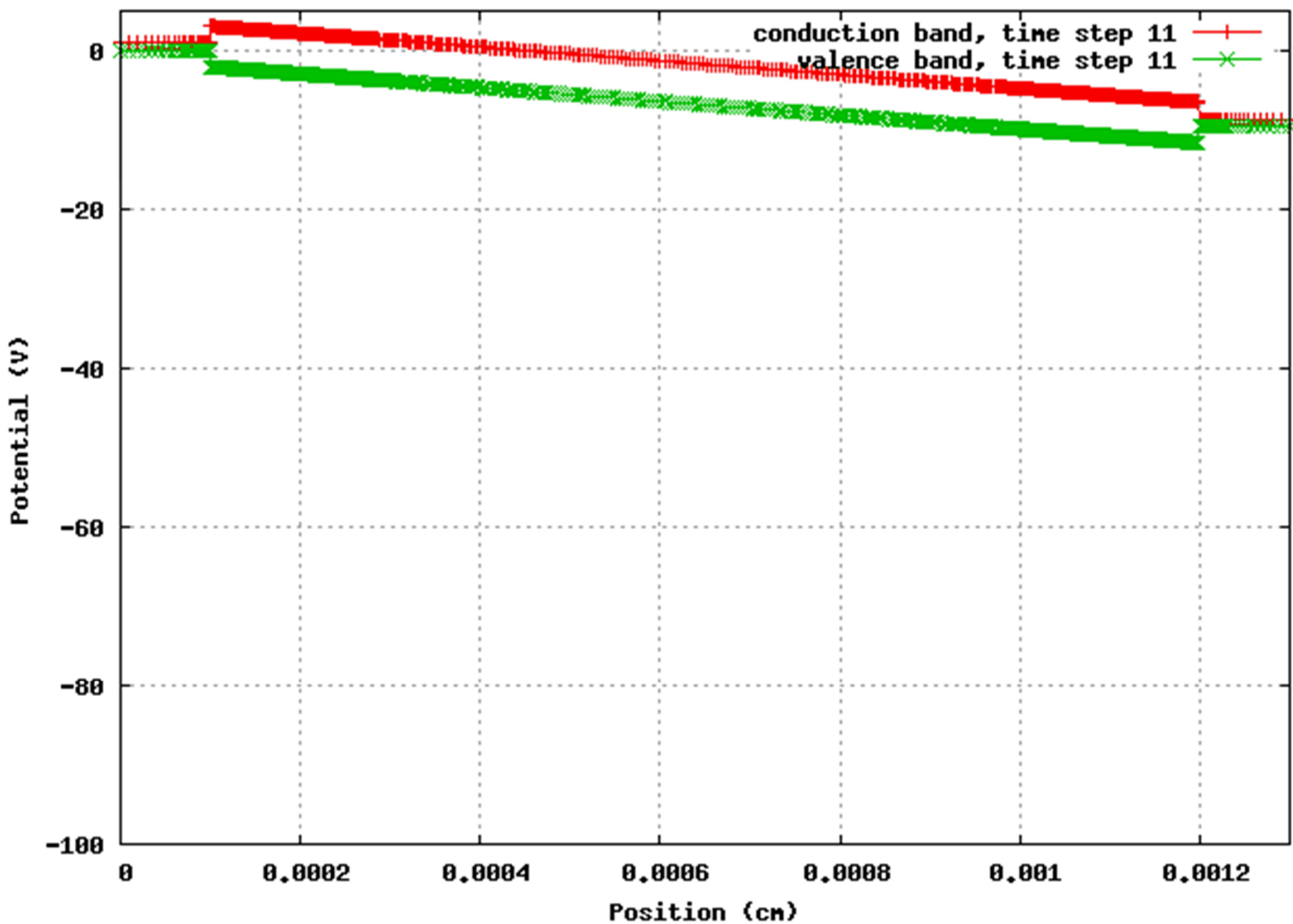
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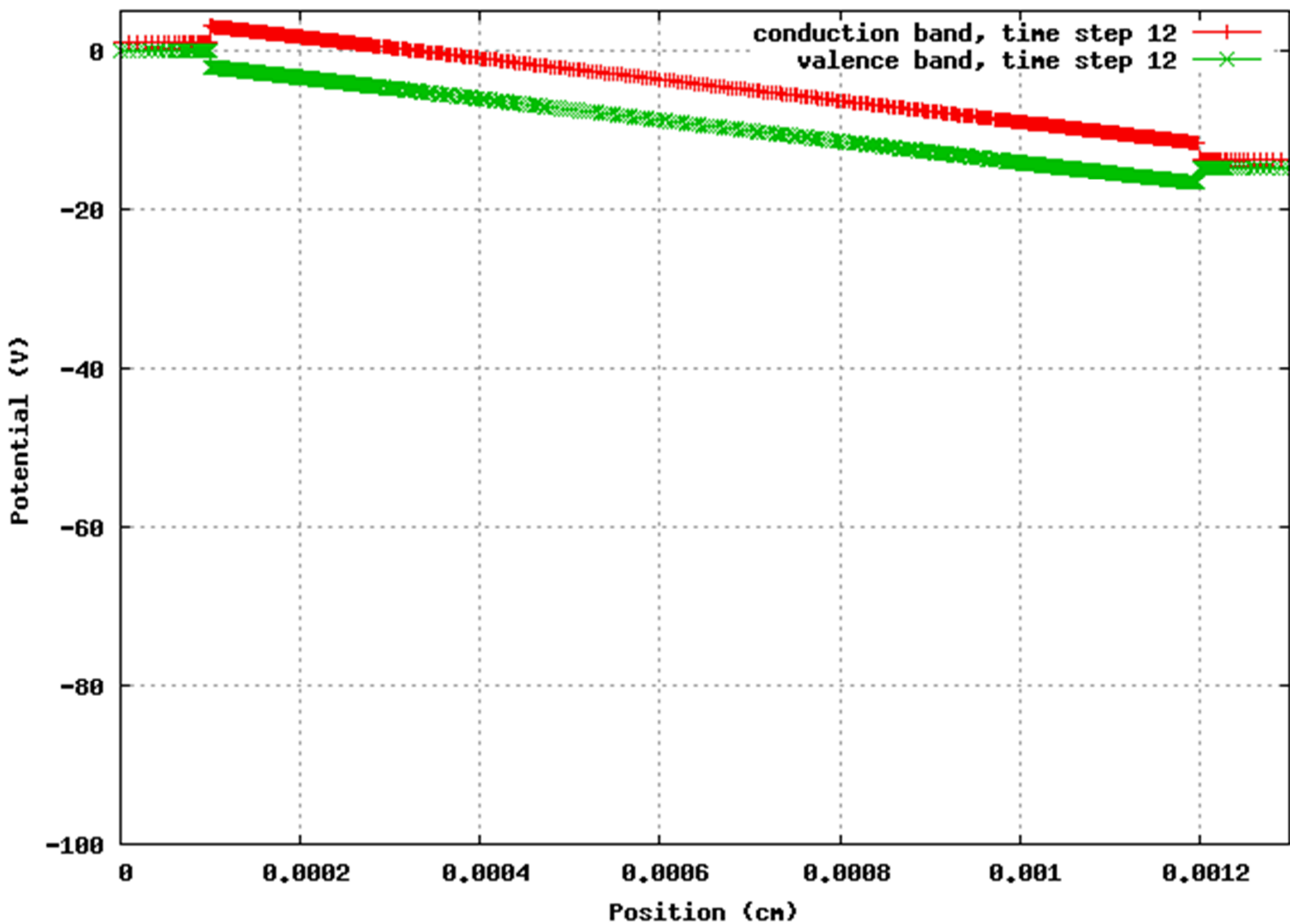
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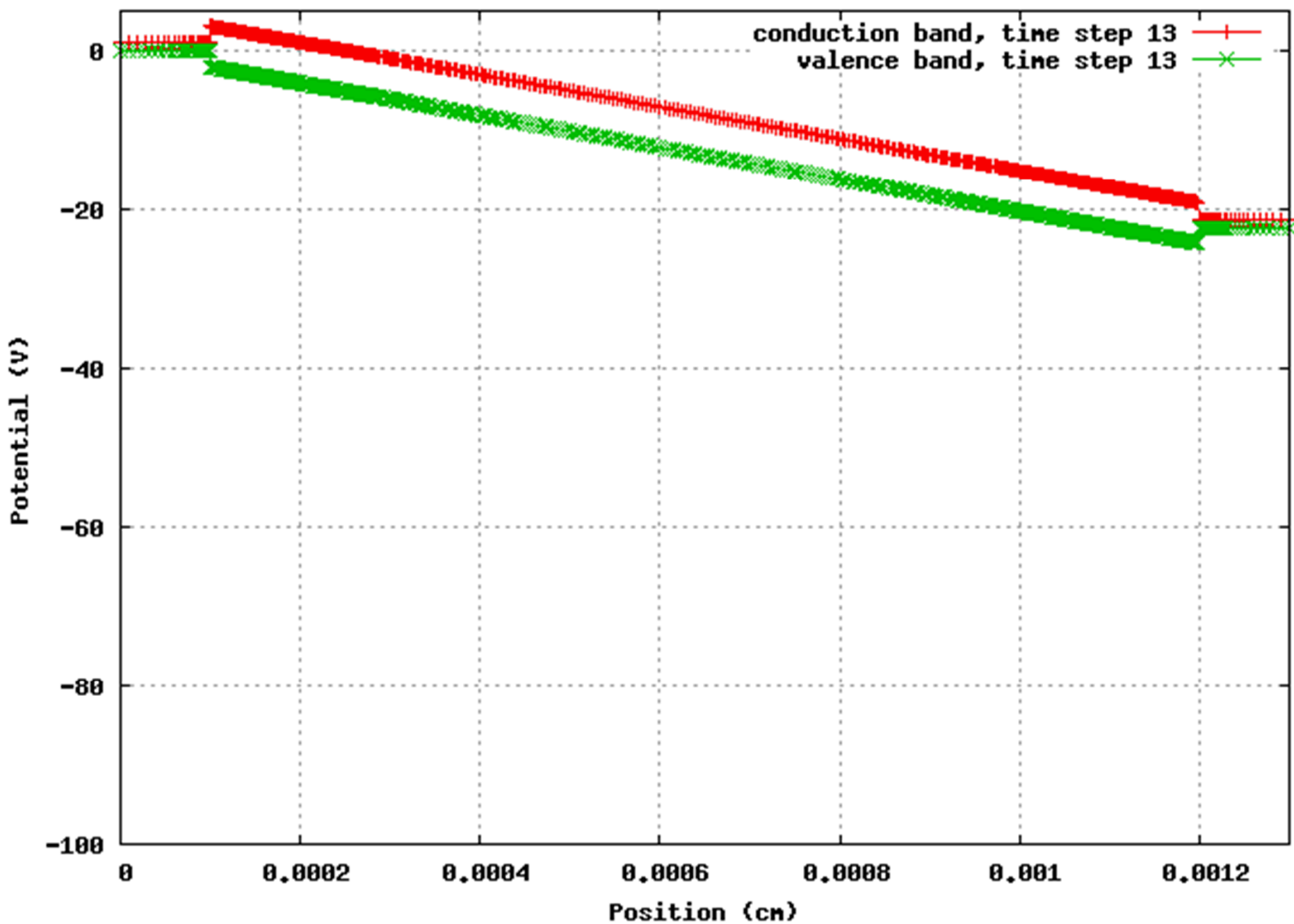
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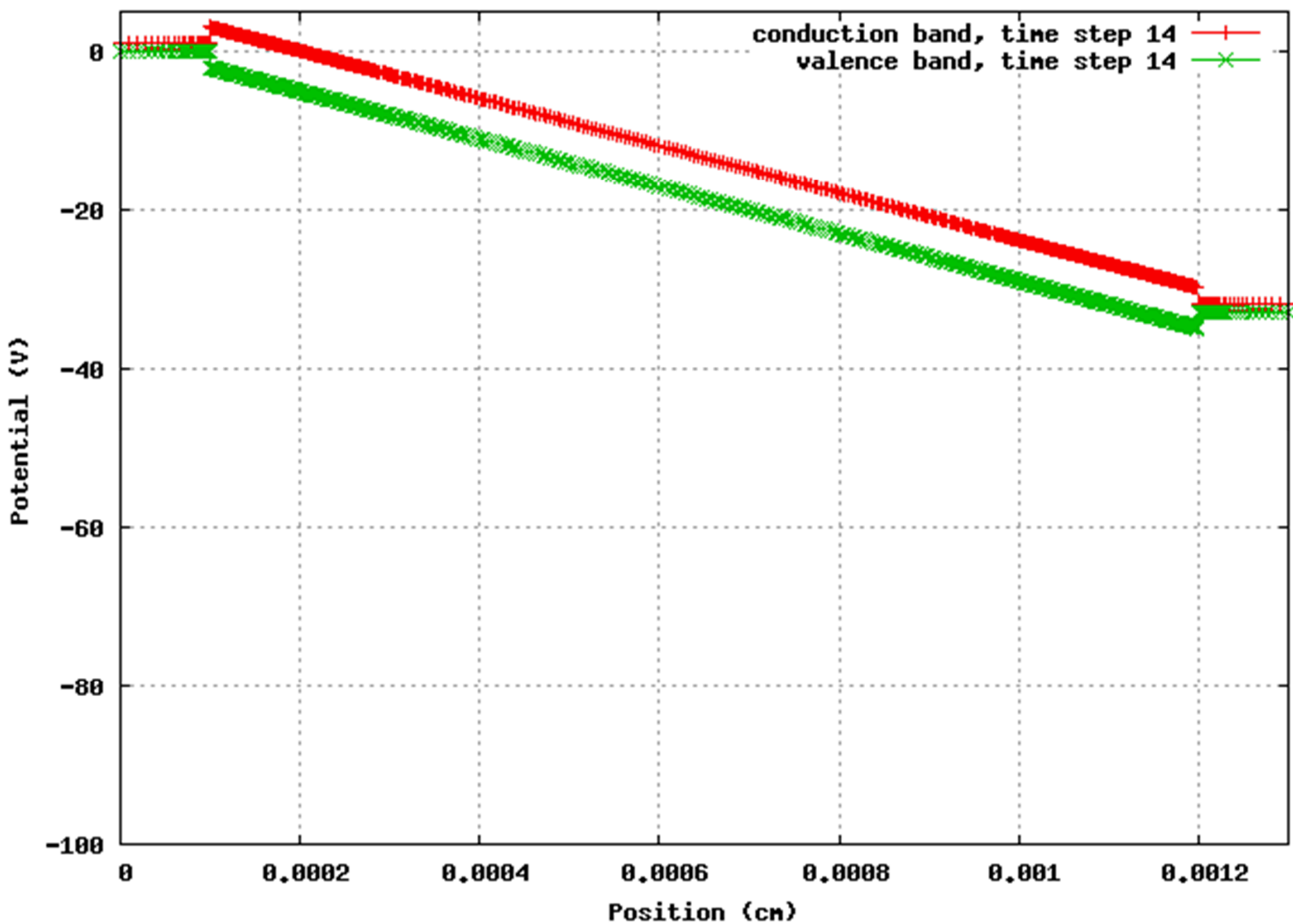
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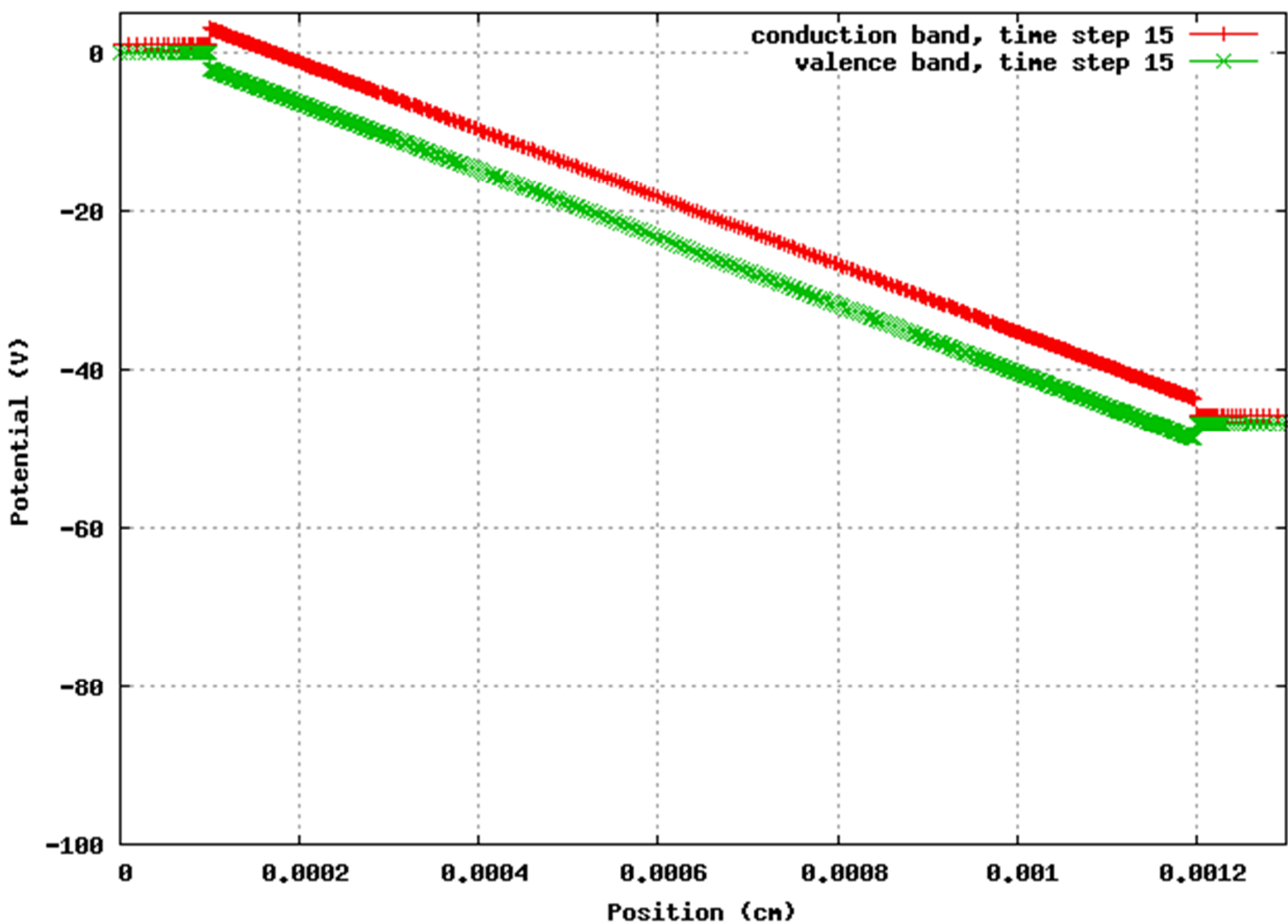
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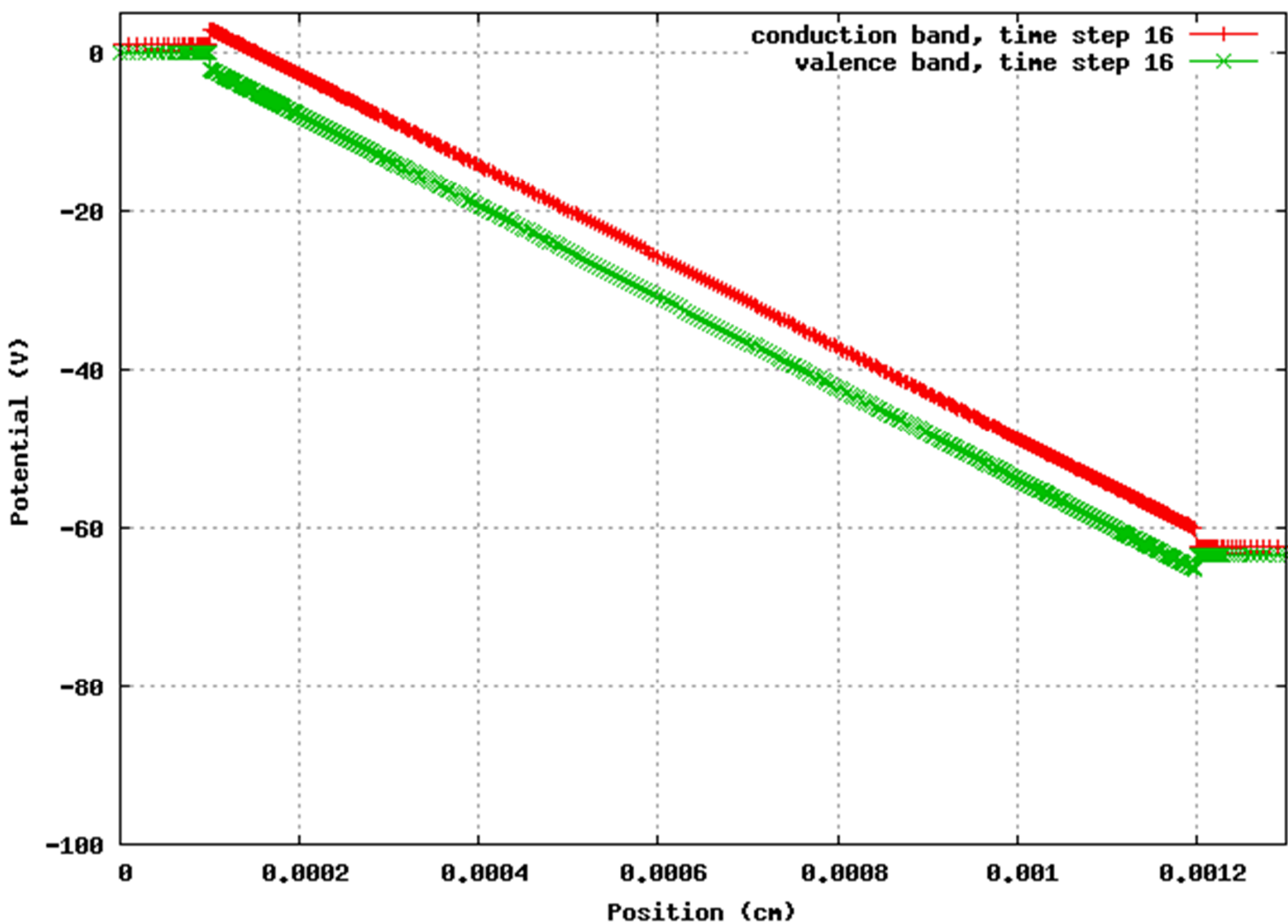
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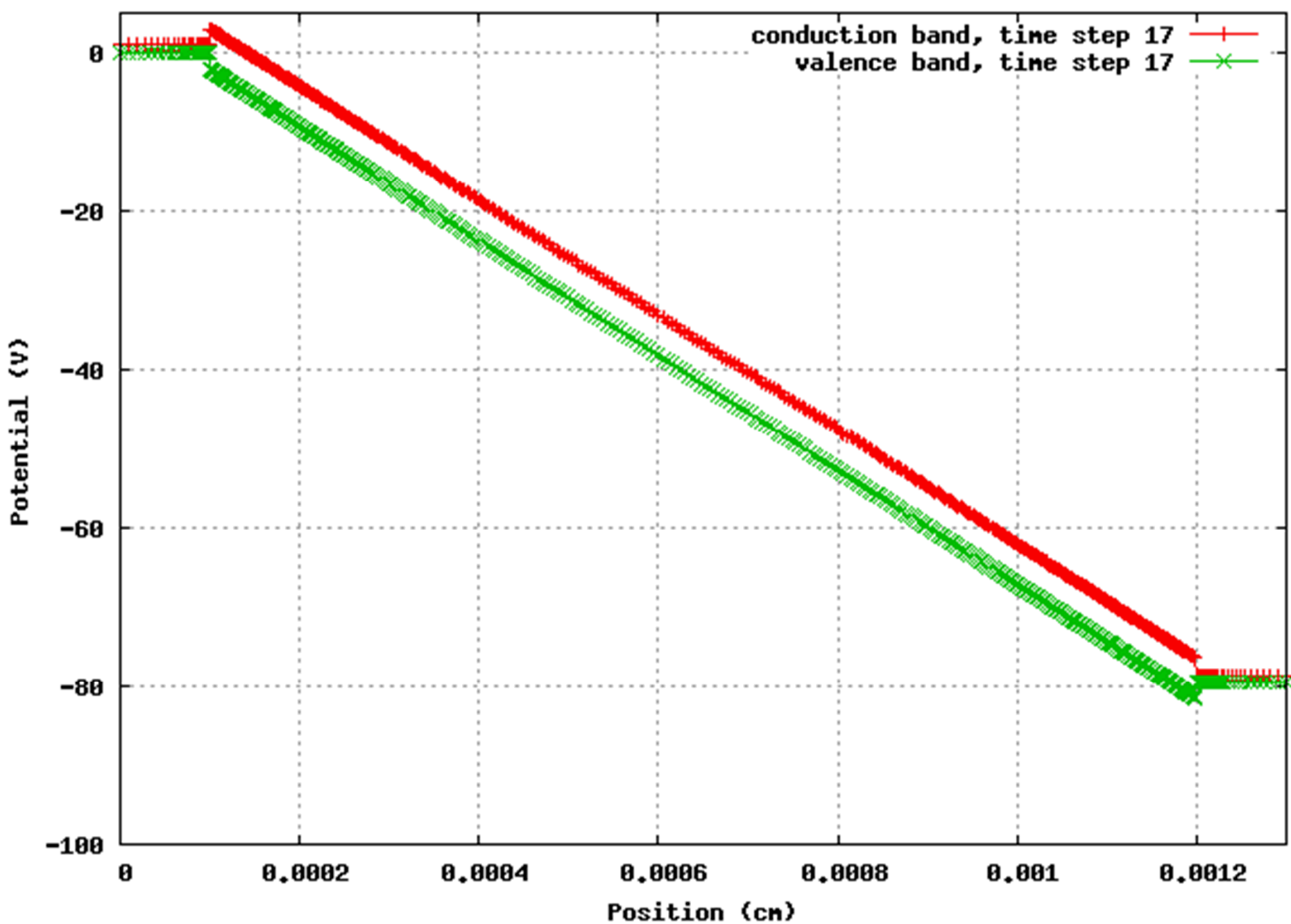
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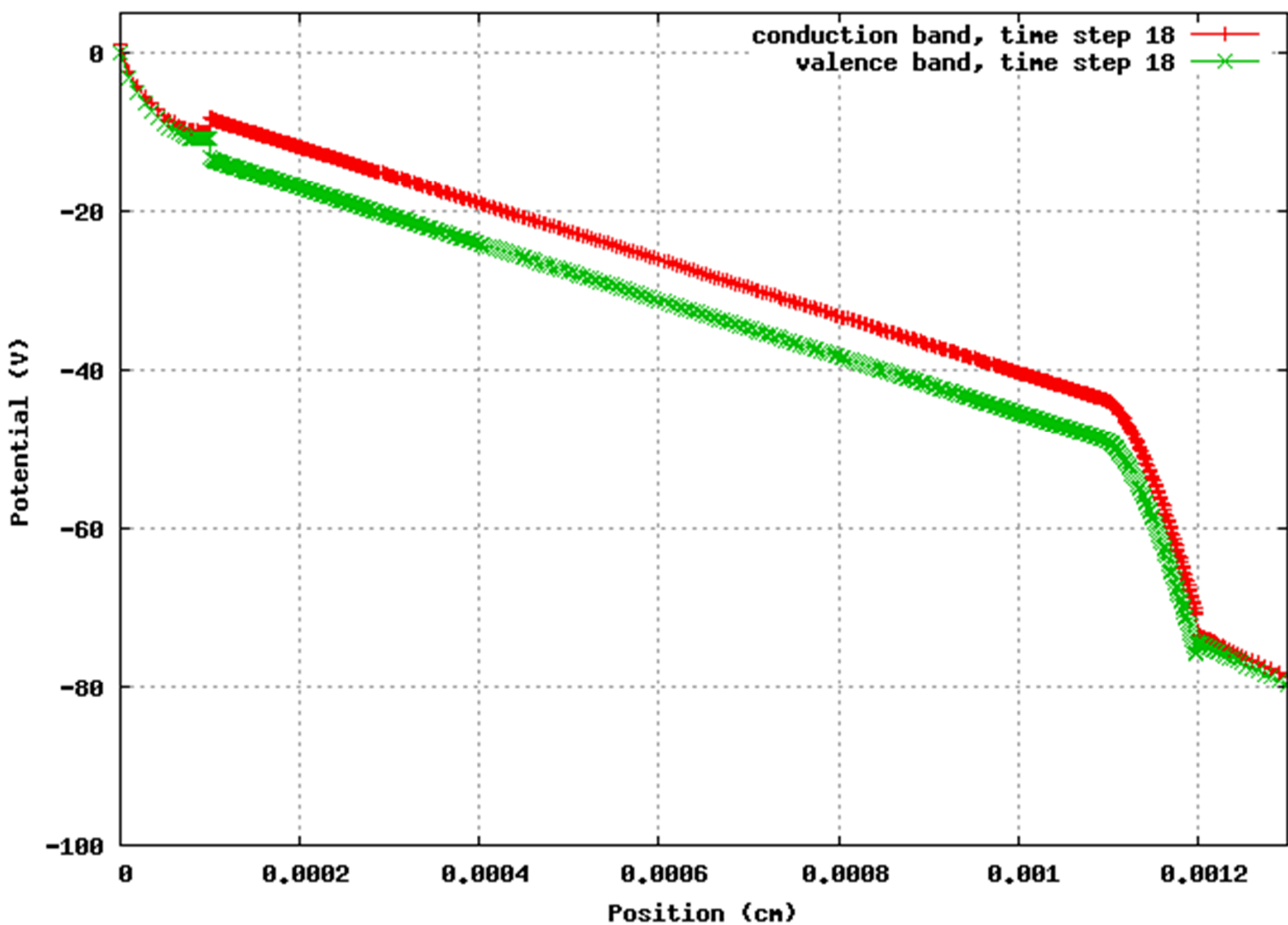
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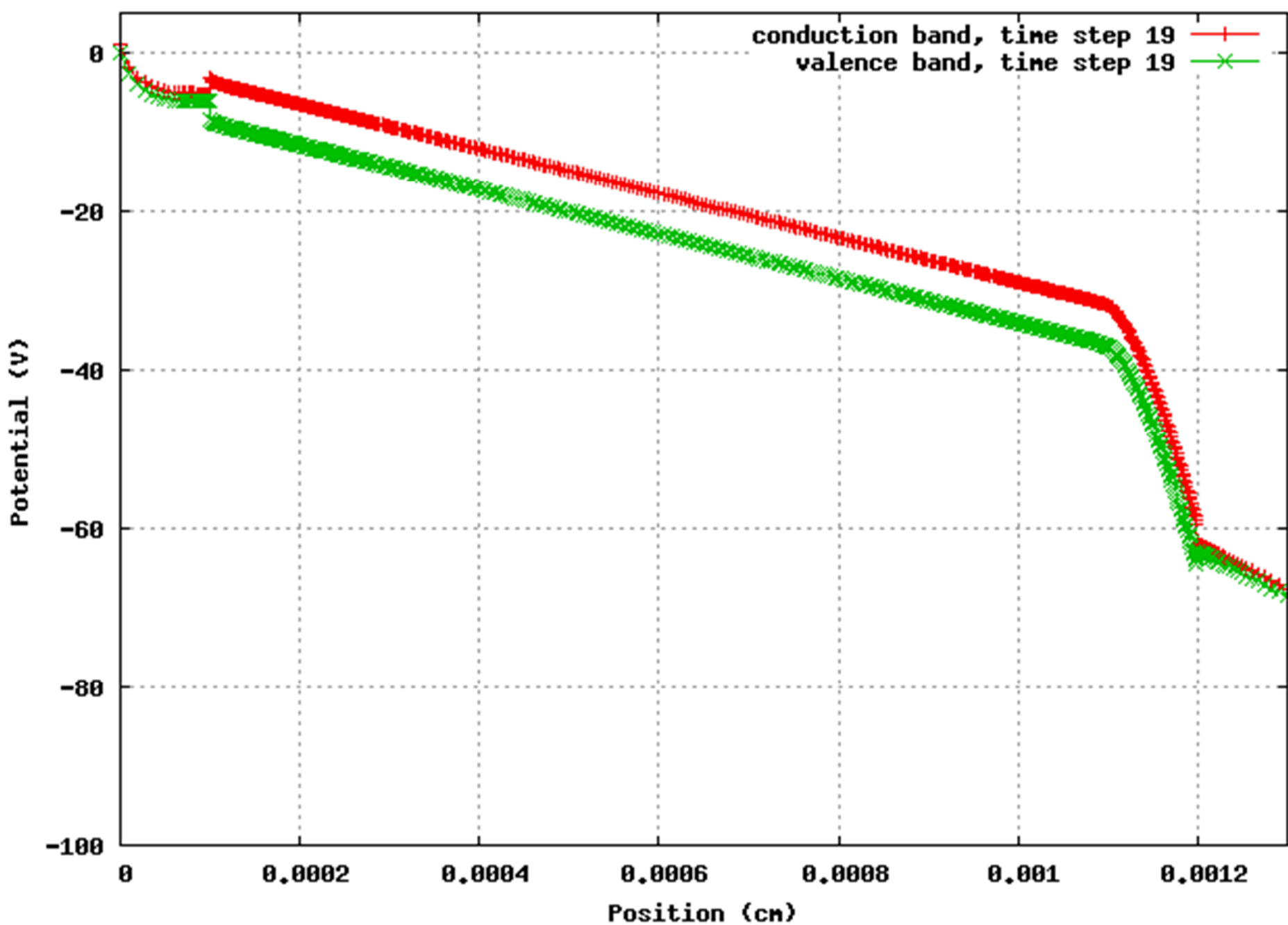
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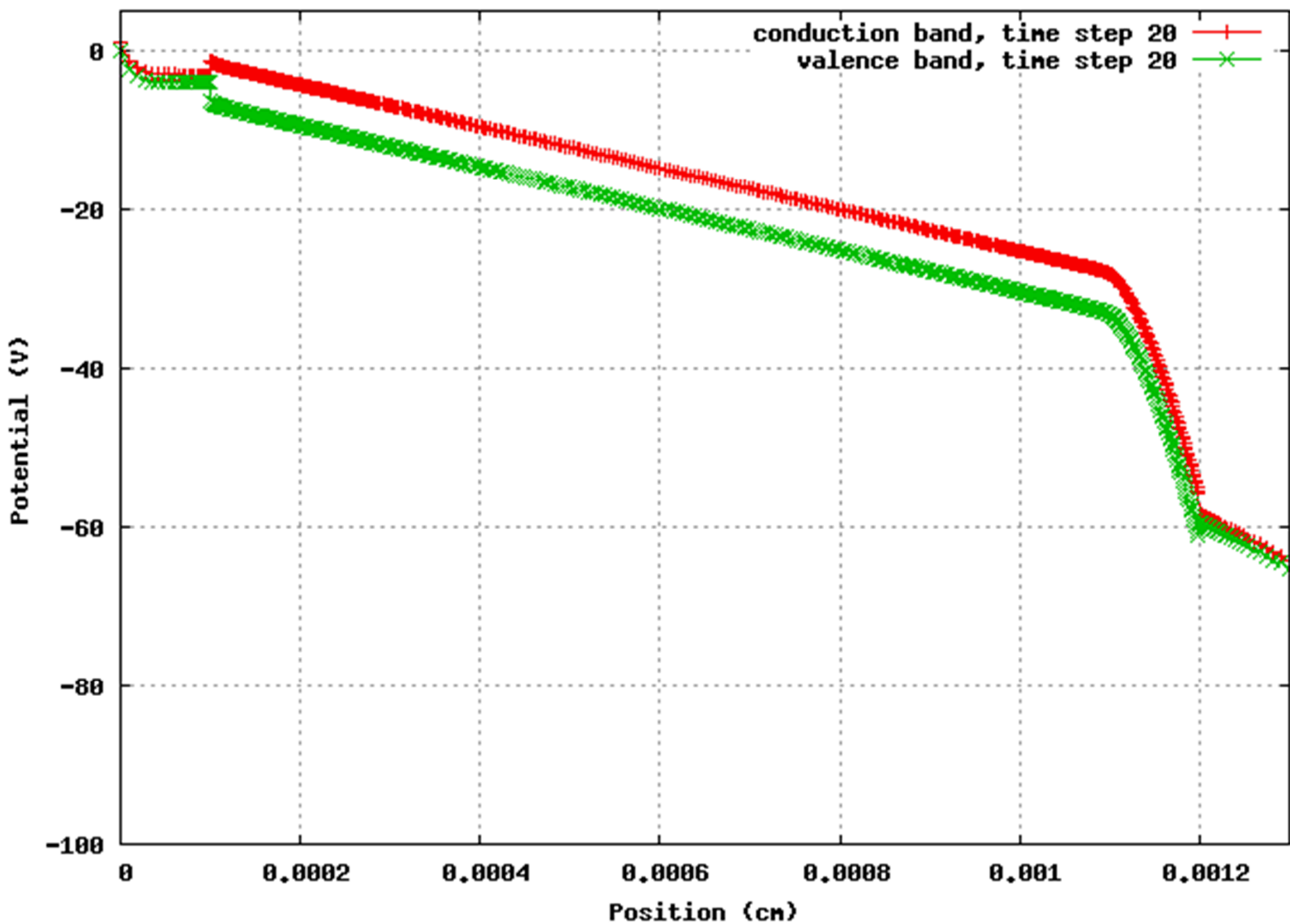
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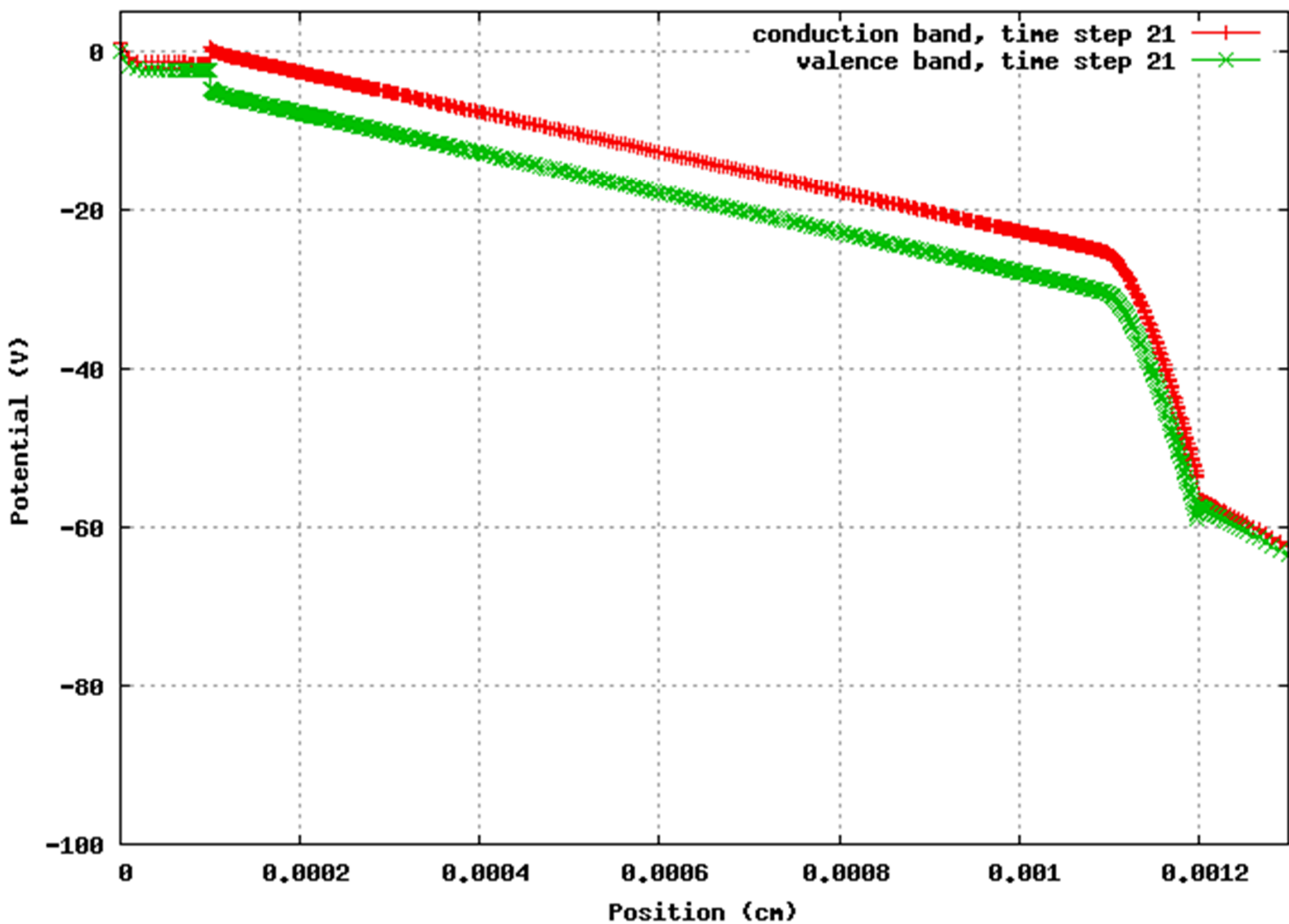
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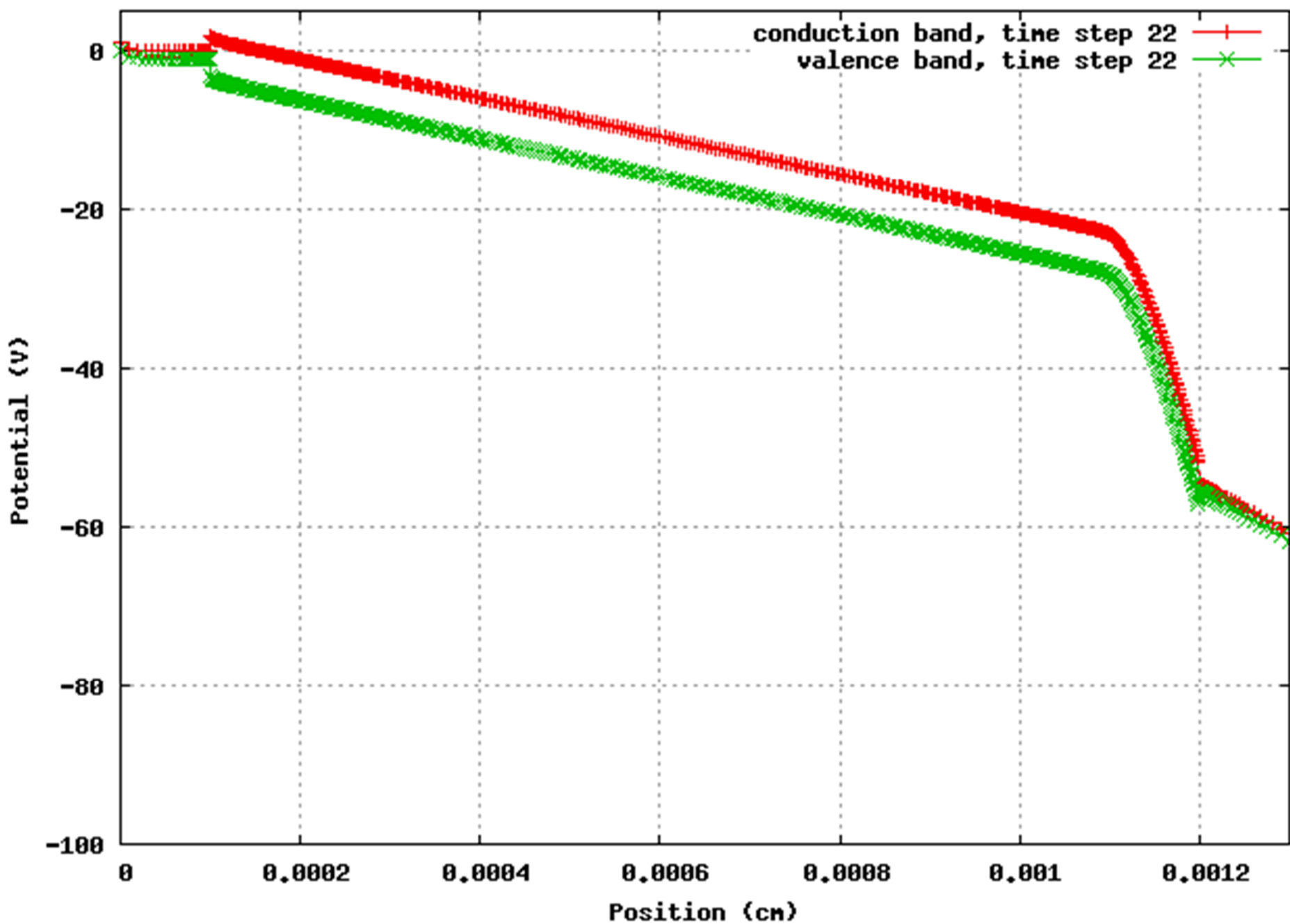
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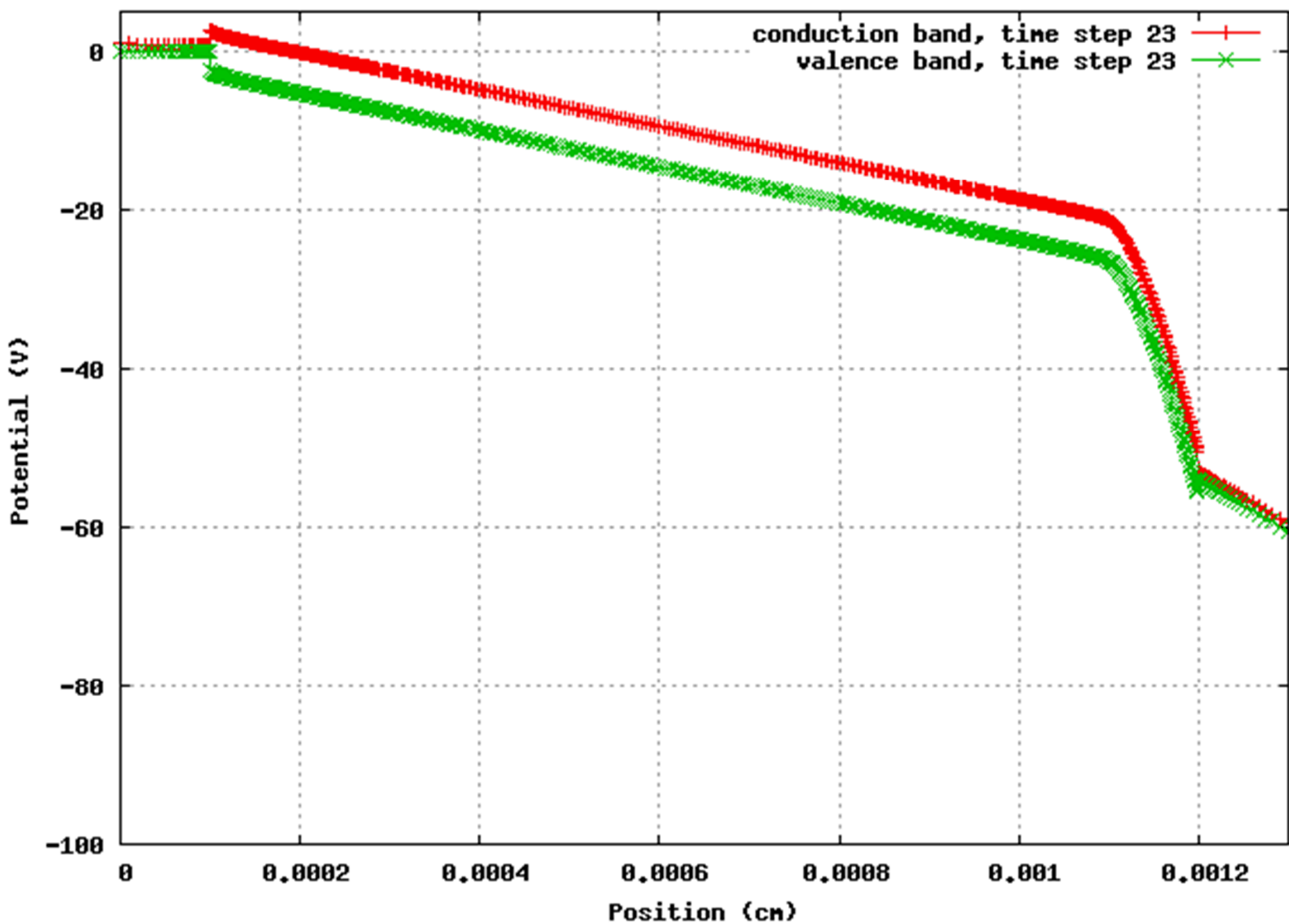
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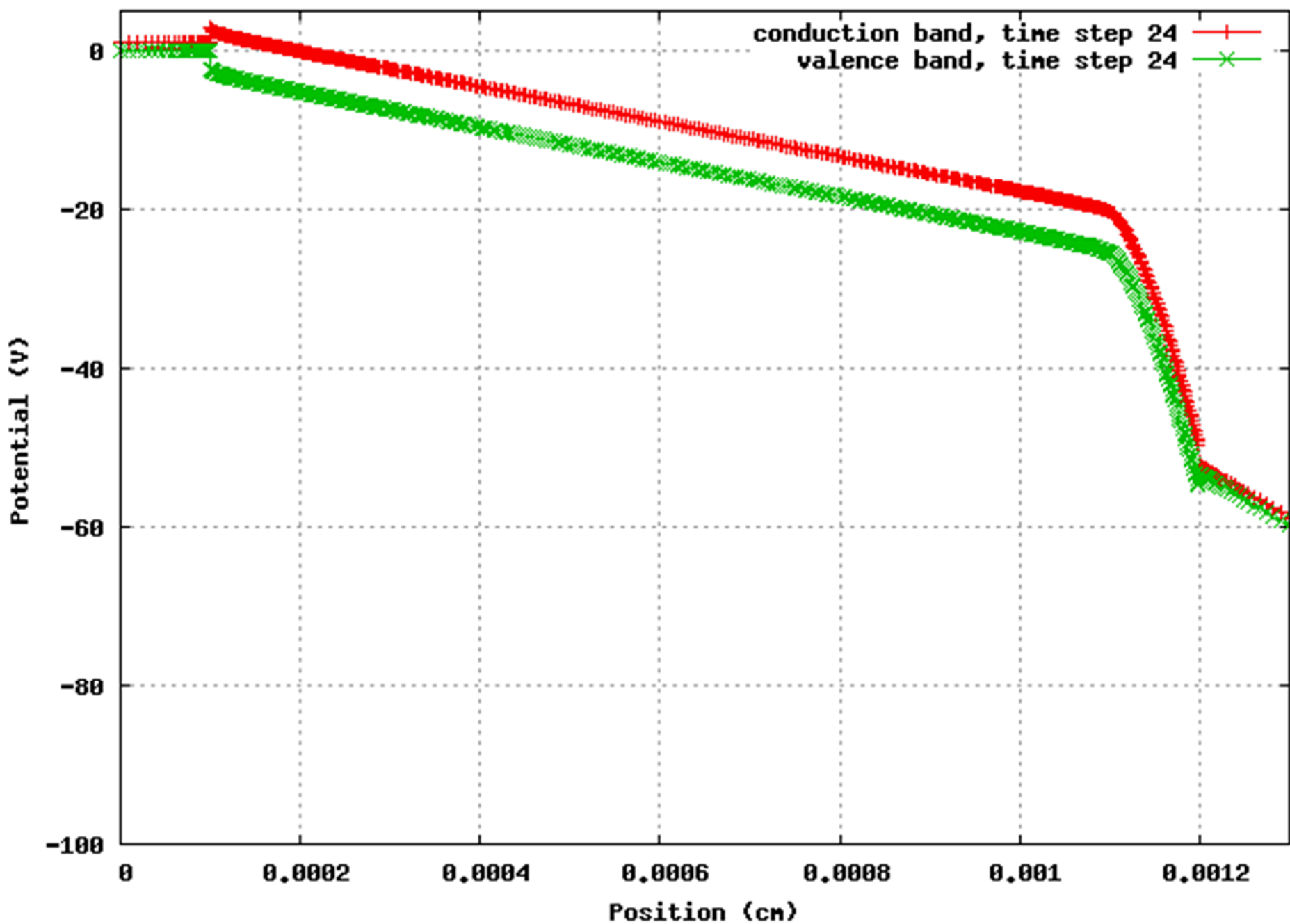
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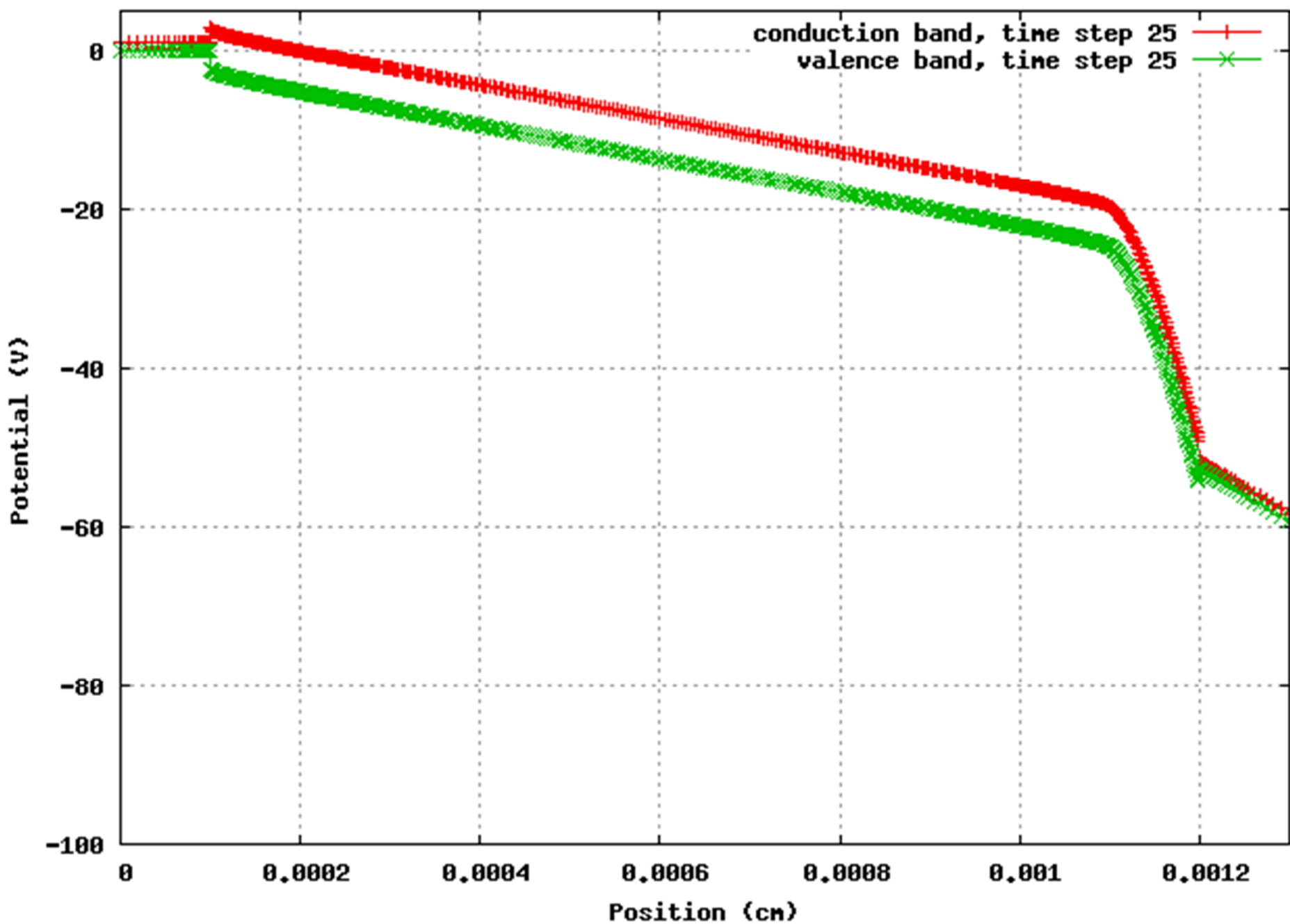
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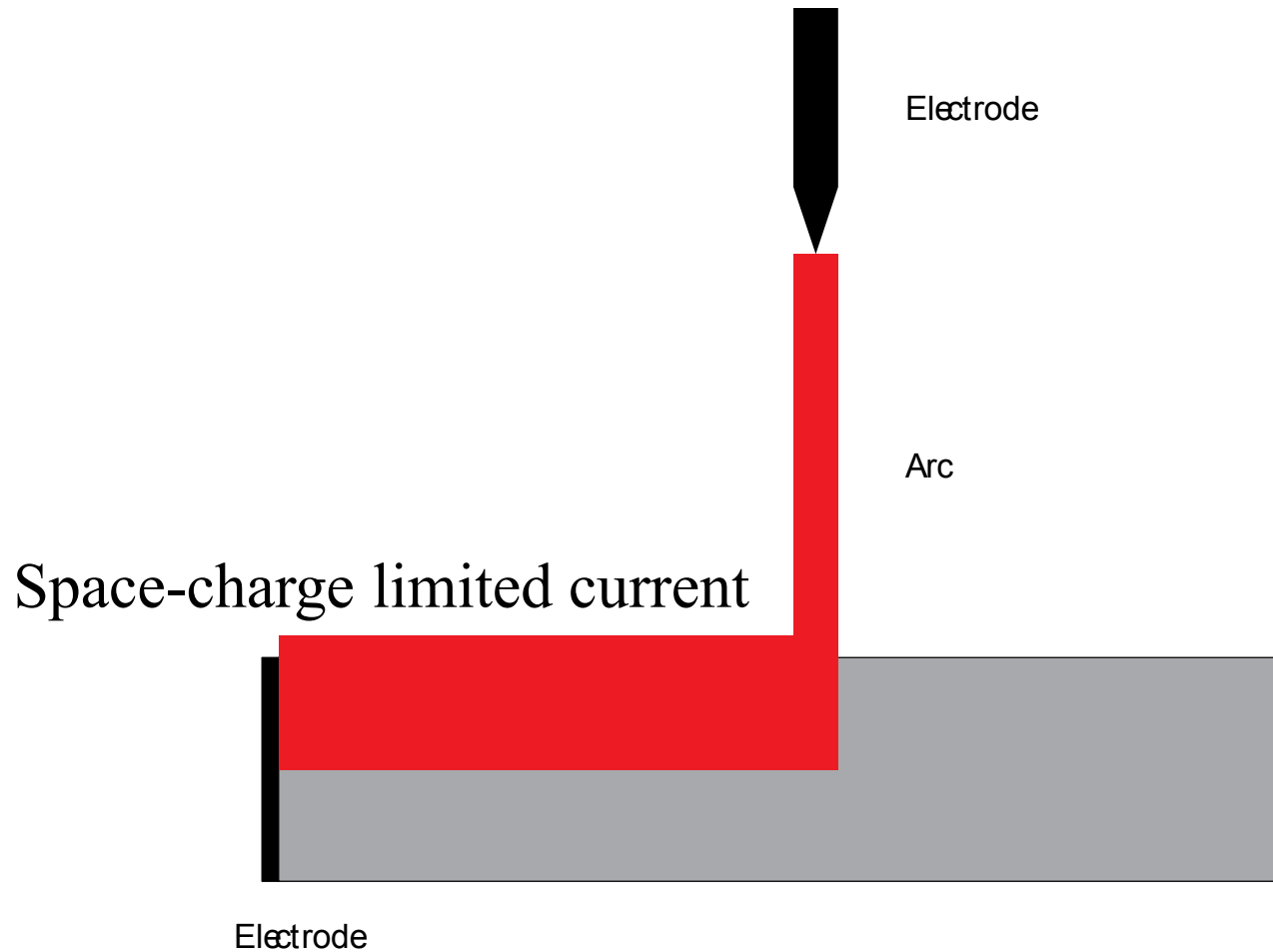
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Extra Slides

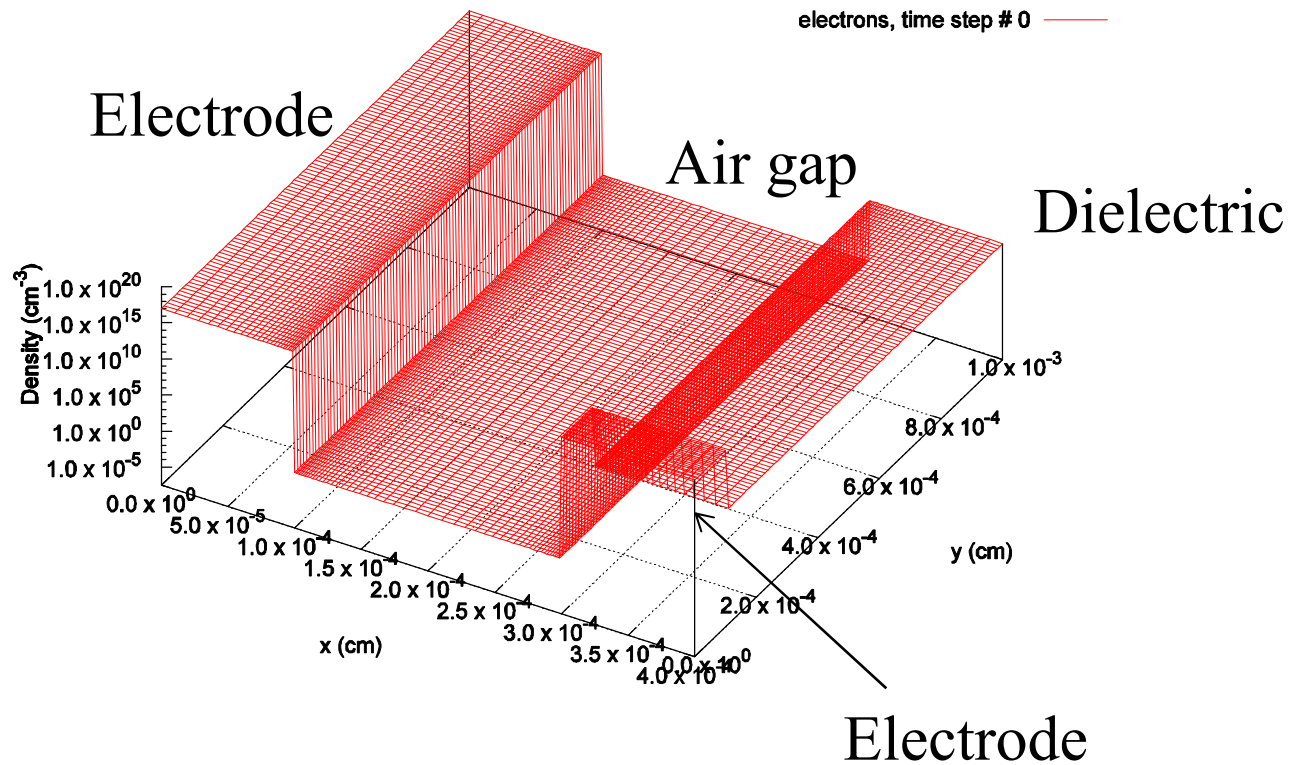


Idealized Experiments: Lateral



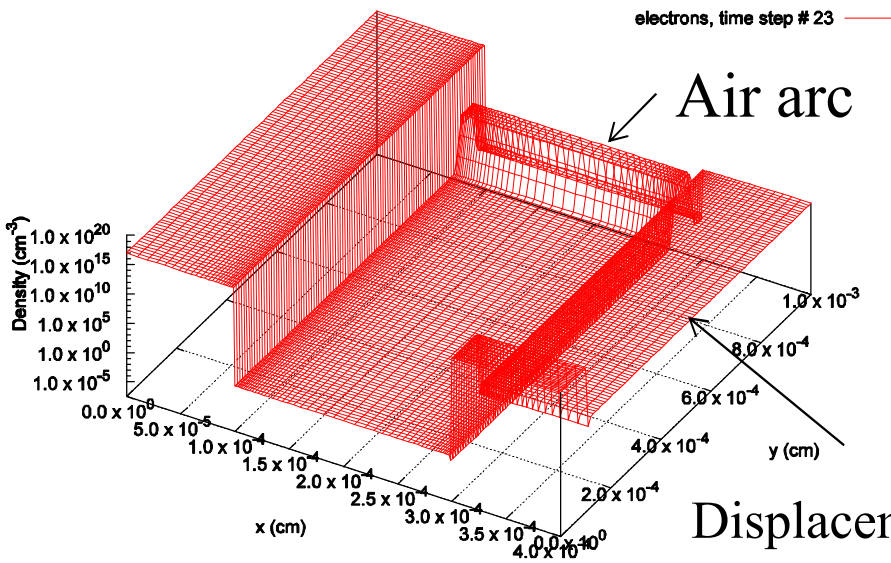
REOS results will illustrate the stages

Lateral Breakdown

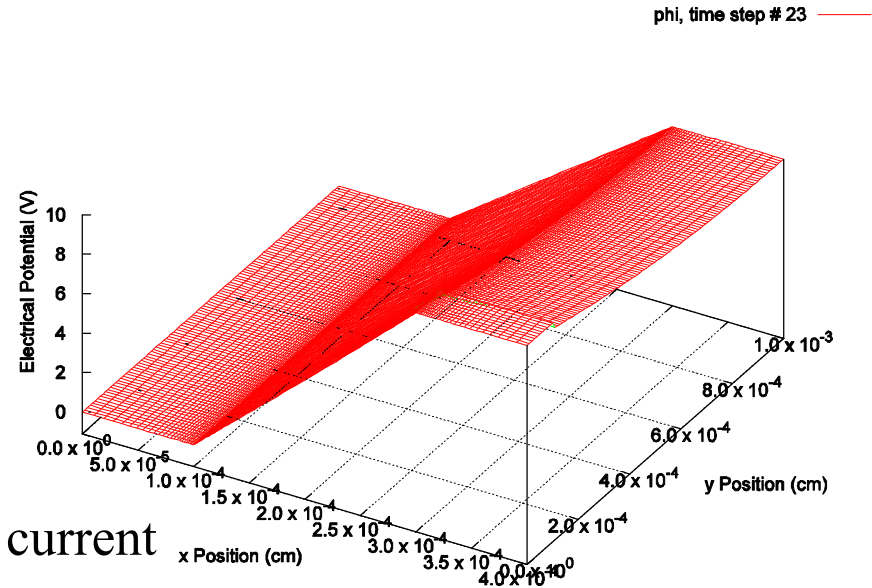


Dielectric constant: 80

Early Stage of Air Breakdown



Displacement current

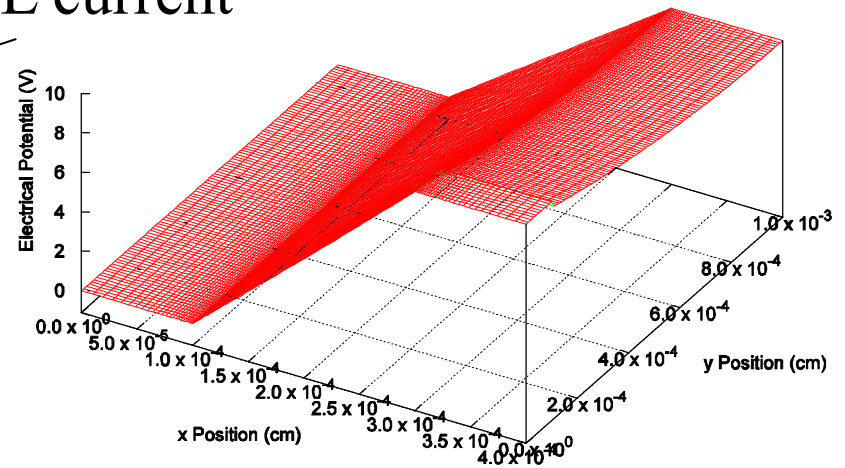
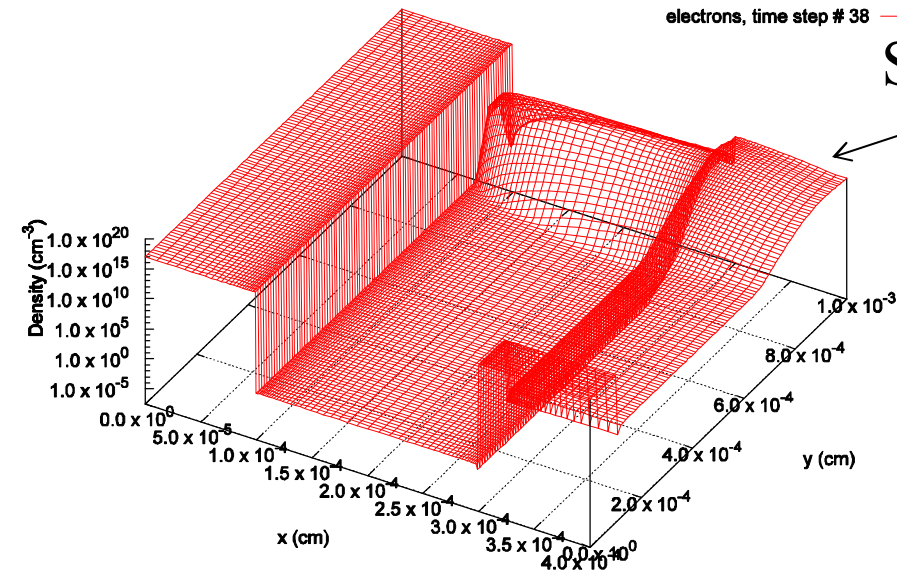


Intermediate Stage

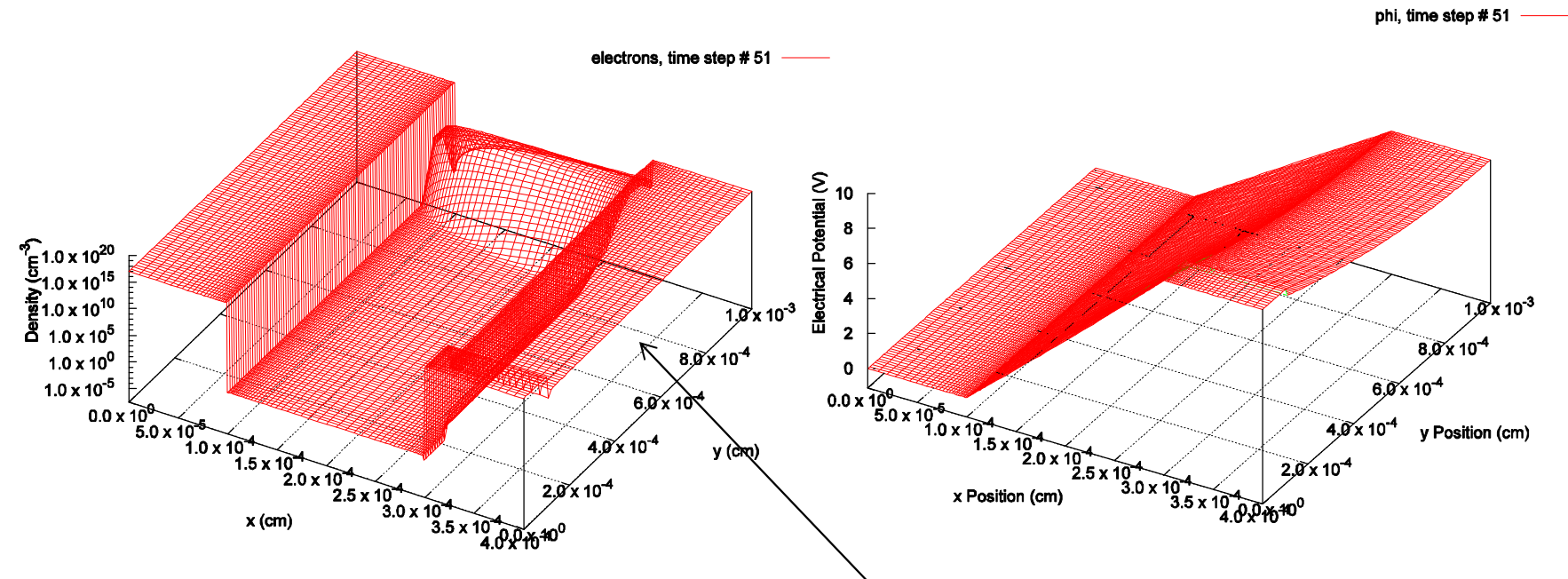
phi, time step # 38

electrons, time step # 38

SCL current



Late Stage



Large SCL current

Joule heating from a large SCL current
causes electrothermal breakdown

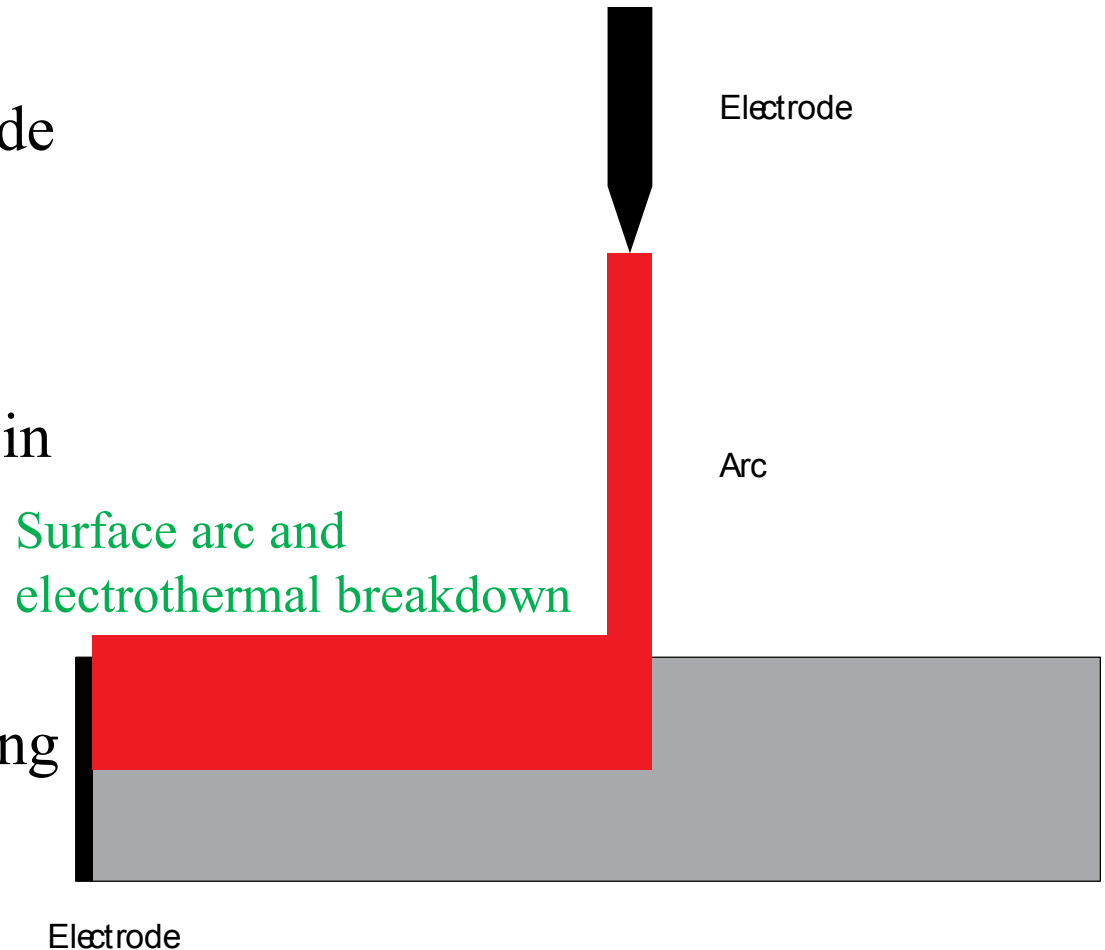


Summary

Short times: The insulating dielectric acts like an electrode to cause air breakdown

Intermediate times: Space charge limited current flows in the solid dielectric

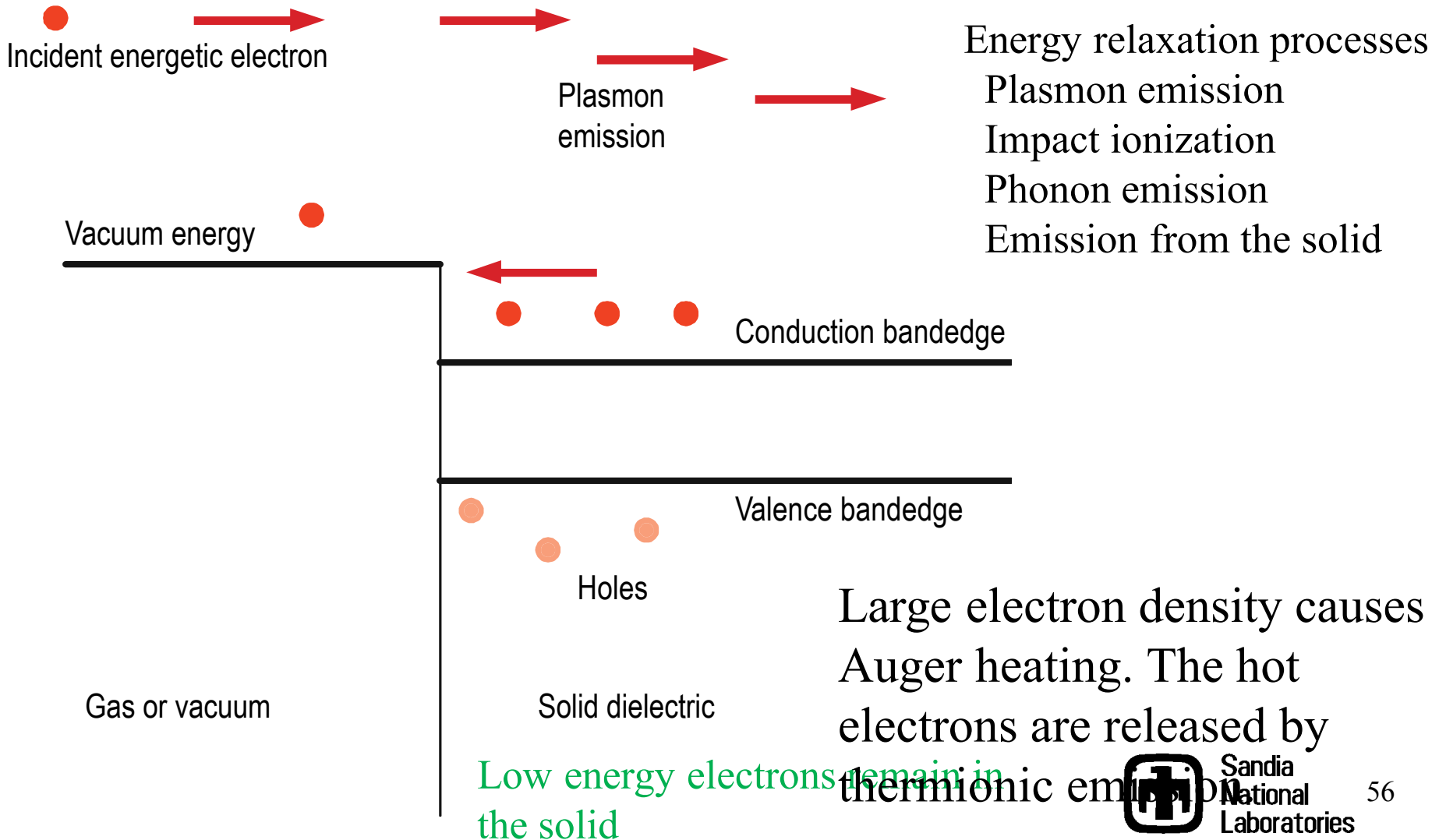
Long times: Electrothermal breakdown from Joule heating



Summary

- **Electrical breakdown with high dielectric constant materials**
 - The solid dielectric appear metallic at short times
 - Electrical breakdown in the solid dielectric
 - Space-charge limited (SCL) current flows
 - SCL current causes Joule heating that increases the conductivity
 - Electrothermal breakdown occurs at long times

Secondary Electron Emission (SEE): Basic Phenomena



Radiation Effects in Oxides and Semiconductors (REOS) Calculations

- **Features**

- Transport
- Energy relaxation
- Chemical reactions
- Heteromaterial interfaces

- **Emphasis**

- Physics
- Simple geometry

- **Method**

- Inject electrons and holes in the RHS insulating region
- Include energy relaxation processes that control the temperature
- Follow evolution in space and temperature



SEE Calculations: Structure

Metal-insulator-insulator-metal

